

Operating Conditions

Stratix® II devices are offered in both commercial and industrial grades. Industrial devices are offered in -4 speed grades and commercial devices are offered in -3 (fastest), -4, -5 speed grades.

Tables 5–1 through 5–32 provide information about absolute maximum ratings, recommended operating conditions, DC electrical characteristics, and other specifications for Stratix II devices.

Absolute Maximum Ratings

Table 5–1 contains the absolute maximum ratings for the Stratix II device family.

Table 5–1. Stratix II Device Absolute Maximum Ratings *Notes (1), (2), (3)*

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V _{CCINT}	Supply voltage	With respect to ground	–0.5	1.8	V
V _{CCIO}	Supply voltage	With respect to ground	–0.5	4.6	V
V _{CCPD}	Supply voltage	With respect to ground	–0.5	4.6	V
V _{CCA}	Analog power supply for PLLs	With respect to ground	–0.5	1.8	V
V _{CCD}	Digital power supply for PLLs	With respect to ground	–0.5	1.8	V
V _I	DC input voltage (4)		–0.5	4.6	V
I _{OUT}	DC output current, per pin		–25	40	mA
T _{STG}	Storage temperature	No bias	–65	150	°C
T _J	Junction temperature	BGA packages under bias	–55	125	°C

Notes to Tables 5–1

- (1) See the *Operating Requirements for Altera Devices Data Sheet*.
- (2) Conditions beyond those listed in Table 5–1 may cause permanent damage to a device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.
- (3) Supply voltage specifications apply to voltage readings taken at the device pins, not at the power supply.
- (4) During transitions, the inputs may overshoot to the voltage shown in Table 5–2 based upon the input duty cycle. The DC case is equivalent to 100% duty cycle. During transitions, the inputs may undershoot to –2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

Table 5–2. Maximum Duty Cycles in Voltage Transitions

Symbol	Parameter	Condition	Maximum Duty Cycles	Unit
V _I	Maximum duty cycles in voltage transitions	V _I = 4.0 V	100	%
		V _I = 4.1 V	90	%
		V _I = 4.2 V	50	%
		V _I = 4.3 V	30	%
		V _I = 4.4 V	17	%
		V _I = 4.5 V	10	%

Recommended Operating Conditions

Table 5–3 contains the Stratix II device family recommended operating conditions.

Table 5–3. Stratix II Device Recommended Operating Conditions (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V _{CCINT}	Supply voltage for internal logic	100 μs ≤ risetime ≤ 100 ms (3)	1.15	1.25	V
V _{CCIO}	Supply voltage for input and output buffers, 3.3-V operation	100 μs ≤ risetime ≤ 100 ms (3), (6)	3.135 (3.00)	3.465 (3.60)	V
	Supply voltage for input and output buffers, 2.5-V operation	100 μs ≤ risetime ≤ 100 ms (3)	2.375	2.625	V
	Supply voltage for input and output buffers, 1.8-V operation	100 μs ≤ risetime ≤ 100 ms (3)	1.71	1.89	V
	Supply voltage for output buffers, 1.5-V operation	100 μs ≤ risetime ≤ 100 ms (3)	1.425	1.575	V
	Supply voltage for input and output buffers, 1.2-V operation	100 μs ≤ risetime ≤ 100 ms (3)	1.14	1.26	V
V _{CCPD}	Supply voltage for pre-drivers as well as configuration and JTAG I/O buffers.	100 μs ≤ risetime ≤ 100 ms (4)	3.135	3.465	V
V _{CCA}	Analog power supply for PLLs	100 μs ≤ risetime ≤ 100 ms (3)	1.15	1.25	V
V _{CCD}	Digital power supply for PLLs	100 μs ≤ risetime ≤ 100 ms (3)	1.15	1.25	V
V _I	Input voltage (see Table 5–2)	(2), (5)	–0.5	4.0	V
V _O	Output voltage		0	V _{CCIO}	V

Table 5–3. Stratix II Device Recommended Operating Conditions (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
T _J	Operating junction temperature	For commercial use	0	85	°C
		For industrial use	–40	100	°C
		For military use (7)	–55	125	°C

Notes to Table 5–3:

- (1) Supply voltage specifications apply to voltage readings taken at the device pins, not at the power supply.
- (2) During transitions, the inputs may overshoot to the voltage shown in Table 5–2 based upon the input duty cycle. The DC case is equivalent to 100% duty cycle. During transitions, the inputs may undershoot to –2.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically from ground to V_{CC}.
- (4) V_{CCPD} must ramp-up from 0 V to 3.3 V within 100 μs to 100 ms. If V_{CCPD} is not ramped up within this specified time, your Stratix II device does not configure successfully. If your system does not allow for a V_{CCPD} ramp-up time of 100 ms or less, you must hold nCONFIG low until all power supplies are reliable.
- (5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT}, V_{CCPD}, and V_{CCIO} are powered.
- (6) V_{CCIO} maximum and minimum conditions for PCI and PCI-X are shown in parentheses.
- (7) For more information, refer to the *Stratix II Military Temperature Range Support* technical brief.

DC Electrical Characteristics

Table 5–4 shows the Stratix II device family DC electrical characteristics.

Table 5–4. Stratix II Device DC Operating Conditions (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit	
I _I	Input pin leakage current	V _I = V _{CCIOmax} to 0 V (2)	–10		10	μA	
I _{OZ}	Tri-stated I/O pin leakage current	V _O = V _{CCIOmax} to 0 V (2)	–10		10	μA	
I _{CCINT0}	V _{CCINT} supply current (standby)	V _I = ground, no load, no toggling inputs T _J = 25° C	EP2S15		0.25	(3)	A
			EP2S30		0.30	(3)	A
			EP2S60		0.50	(3)	A
			EP2S90		0.62	(3)	A
			EP2S130		0.82	(3)	A
			EP2S180		1.12	(3)	A
I _{CCPD0}	V _{CCPD} supply current (standby)	V _I = ground, no load, no toggling inputs T _J = 25° C, V _{CCPD} = 3.3V	EP2S15		2.2	(3)	mA
			EP2S30		2.7	(3)	mA
			EP2S60		3.6	(3)	mA
			EP2S90		4.3	(3)	mA
			EP2S130		5.4	(3)	mA
			EP2S180		6.8	(3)	mA

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit	
I_{CCIO}	V_{CCIO} supply current (standby)	$V_I =$ ground, no load, no toggling inputs $T_J = 25^\circ\text{C}$	EP2S15		4.0	(3)	mA
			EP2S30		4.0	(3)	mA
			EP2S60		4.0	(3)	mA
			EP2S90		4.0	(3)	mA
			EP2S130		4.0	(3)	mA
			EP2S180		4.0	(3)	mA
R_{CONF} (4)	Value of I/O pin pull-up resistor before and during configuration	$V_i = 0; V_{CCIO} = 3.3\text{ V}$	10	25	50	k Ω	
		$V_i = 0; V_{CCIO} = 2.5\text{ V}$	15	35	70	k Ω	
		$V_i = 0; V_{CCIO} = 1.8\text{ V}$	30	50	100	k Ω	
		$V_i = 0; V_{CCIO} = 1.5\text{ V}$	40	75	150	k Ω	
		$V_i = 0; V_{CCIO} = 1.2\text{ V}$	50	90	170	k Ω	
	Recommended value of I/O pin external pull-down resistor before and during configuration				1	2	k Ω

Notes to Table 5–4:

- (1) Typical values are for $T_A = 25^\circ\text{C}$, $V_{CCINT} = 1.2\text{ V}$, and $V_{CCIO} = 1.5\text{ V}, 1.8\text{ V}, 2.5\text{ V}$, and 3.3 V .
- (2) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).
- (3) Maximum values depend on the actual T_J and design utilization. See the Excel-based PowerPlay Early Power Estimator (available at www.altera.com) or the Quartus II PowerPlay Power Analyzer feature for maximum values. See the section “Power Consumption” on page 5–20 for more information.
- (4) Pin pull-up resistance values are lower if an external source drives the pin higher than V_{CCIO} .

I/O Standard Specifications

Tables 5–5 through 5–32 show the Stratix II device family I/O standard specifications.

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} (1)	Output supply voltage		3.135	3.465	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
V_{OH}	High-level output voltage	$I_{OH} = -4\text{ mA}$ (2)	2.4		V

Table 5–5. LVTTTL Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{OL}	Low-level output voltage	$I_{OL} = 4 \text{ mA}$ (2)		0.45	V

Notes to Tables 5–5:

- (1) Stratix II devices comply to the narrow range for the supply voltage as specified in the EIA/JEDEC Standard, JESD8-B.
- (2) This specification is supported across all the programmable drive strength settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–6. LVCMOS Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} (1)	Output supply voltage		3.135	3.465	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
V_{OH}	High-level output voltage	$V_{CCIO} = 3.0$, $I_{OH} = -0.1 \text{ mA}$ (2)	$V_{CCIO} - 0.2$		V
V_{OL}	Low-level output voltage	$V_{CCIO} = 3.0$, $I_{OL} = 0.1 \text{ mA}$ (2)		0.2	V

Notes to Table 5–6:

- (1) Stratix II devices comply to the narrow range for the supply voltage as specified in the EIA/JEDEC Standard, JESD8-B.
- (2) This specification is supported across all the programmable drive strength available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–7. 2.5-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} (1)	Output supply voltage		2.375	2.625	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.7	V
V_{OH}	High-level output voltage	$I_{OH} = -1 \text{ mA}$ (2)	2.0		V
V_{OL}	Low-level output voltage	$I_{OL} = 1 \text{ mA}$ (2)		0.4	V

Notes to Table 5–7:

- (1) Stratix II devices V_{CCIO} voltage level support of $2.5 \pm -5\%$ is narrower than defined in the Normal Range of the EIA/JEDEC standard.
- (2) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–8. 1.8-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} (1)	Output supply voltage		1.71	1.89	V
V_{IH}	High-level input voltage		$0.65 \times V_{CCIO}$	2.25	V
V_{IL}	Low-level input voltage		-0.30	$0.35 \times V_{CCIO}$	V
V_{OH}	High-level output voltage	$I_{OH} = -2 \text{ mA}$ (2)	$V_{CCIO} - 0.45$		V
V_{OL}	Low-level output voltage	$I_{OL} = 2 \text{ mA}$ (2)		0.45	V

Notes to Table 5–8:

- (1) The Stratix II device family's V_{CCIO} voltage level support of $1.8 \pm 5\%$ is narrower than defined in the Normal Range of the EIA/JEDEC standard.
- (2) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–9. 1.5-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} (1)	Output supply voltage		1.425	1.575	V
V_{IH}	High-level input voltage		$0.65 \times V_{CCIO}$	$V_{CCIO} + 0.30$	V
V_{IL}	Low-level input voltage		-0.30	$0.35 \times V_{CCIO}$	V
V_{OH}	High-level output voltage	$I_{OH} = -2 \text{ mA}$ (2)	$0.75 \times V_{CCIO}$		V
V_{OL}	Low-level output voltage	$I_{OL} = 2 \text{ mA}$ (2)		$0.25 \times V_{CCIO}$	V

Notes to Table 5–9:

- (1) The Stratix II device family's V_{CCIO} voltage level support of $1.5 \pm 5\%$ is narrower than defined in the Normal Range of the EIA/JEDEC standard.
- (2) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Figures 5–1 and 5–2 show receiver input and transmitter output waveforms, respectively, for all differential I/O standards (LVDS, LVPECL, and HyperTransport technology).

Figure 5–1. Receiver Input Waveforms for Differential I/O Standards

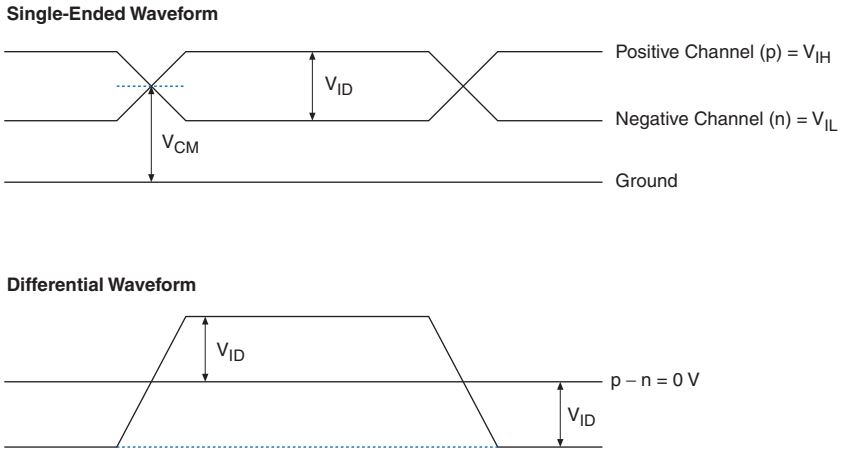


Figure 5–2. Transmitter Output Waveforms for Differential I/O Standards

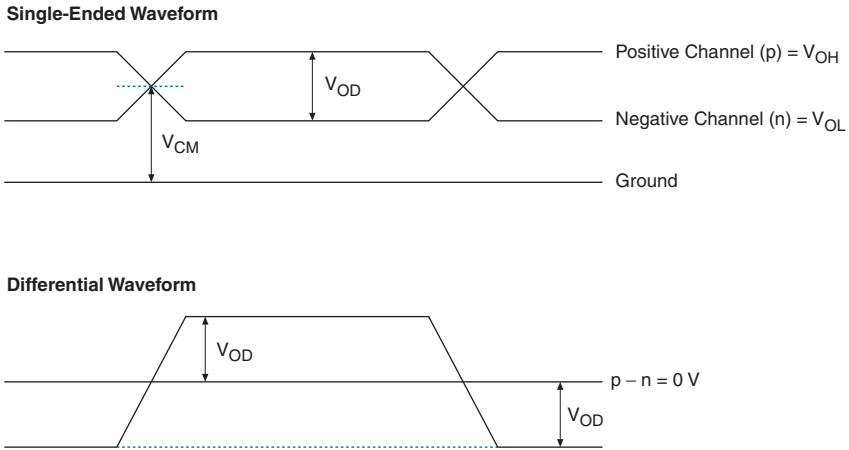


Table 5–10. 2.5-V LVDS I/O Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	I/O supply voltage for left and right I/O banks (1, 2, 5, and 6)		2.375	2.500	2.625	V
V _{ID}	Input differential voltage swing (single-ended)		100	350	900	mV
V _{ICM}	Input common mode voltage		200	1,250	1,800	mV
V _{OD}	Output differential voltage (single-ended)	R _L = 100 Ω	250		450	mV
V _{OCM}	Output common mode voltage	R _L = 100 Ω	1.125		1.375	V
R _L	Receiver differential input discrete resistor (external to Stratix II devices)		90	100	110	Ω

Table 5–11. 3.3-V LVDS I/O Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO} (1)	I/O supply voltage for top and bottom PLL banks (9, 10, 11, and 12)		3.135	3.300	3.465	V
V _{ID}	Input differential voltage swing (single-ended)		100	350	900	mV
V _{ICM}	Input common mode voltage		200	1,250	1,800	mV
V _{OD}	Output differential voltage (single-ended)	R _L = 100 Ω	250		710	mV
V _{OCM}	Output common mode voltage	R _L = 100 Ω	840		1,570	mV
R _L	Receiver differential input discrete resistor (external to Stratix II devices)		90	100	110	Ω

Note to Table 5–11:

- (1) The top and bottom clock input differential buffers in I/O banks 3, 4, 7, and 8 are powered by V_{CCINT}, not V_{CCIO}. The PLL clock output/feedback differential buffers are powered by VCC_PLL_OUT. For differential clock output/feedback operation, VCC_PLL_OUT should be connected to 3.3 V.

Table 5–12. LVPECL Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO} (1)	I/O supply voltage		3.135	3.300	3.465	V
V_{ID}	Input differential voltage swing (single-ended)		300	600	1,000	mV
V_{ICM}	Input common mode voltage		1.0		2.5	V
V_{OD}	Output differential voltage (single-ended)	$R_L = 100 \Omega$	525		970	mV
V_{OCM}	Output common mode voltage	$R_L = 100 \Omega$	1,650		2,250	mV
R_L	Receiver differential input resistor		90	100	110	Ω

Note to Table 5–12:

- (1) The top and bottom clock input differential buffers in I/O banks 3, 4, 7, and 8 are powered by V_{CCINT} , not V_{CCIO} . The PLL clock output/feedback differential buffers are powered by VCC_PLL_OUT . For differential clock output/feedback operation, VCC_PLL_OUT should be connected to 3.3 V.

Table 5–13. HyperTransport Technology Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage for left and right I/O banks (1, 2, 5, and 6)		2.375	2.500	2.625	V
V_{ID}	Input differential voltage swing (single-ended)	$R_L = 100 \Omega$	300	600	900	mV
V_{ICM}	Input common mode voltage	$R_L = 100 \Omega$	385	600	845	mV
V_{OD}	Output differential voltage (single-ended)	$R_L = 100 \Omega$	400	600	820	mV
ΔV_{OD}	Change in V_{OD} between high and low	$R_L = 100 \Omega$			75	mV
V_{OCM}	Output common mode voltage	$R_L = 100 \Omega$	440	600	780	mV
ΔV_{OCM}	Change in V_{OCM} between high and low	$R_L = 100 \Omega$			50	mV
R_L	Receiver differential input resistor		90	100	110	Ω

Table 5–14. 3.3-V PCI Specifications (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		3.0	3.3	3.6	V
V_{IH}	High-level input voltage		$0.5 \times V_{CCIO}$		$V_{CCIO} + 0.5$	V

Table 5–14. 3.3-V PCI Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{IL}	Low-level input voltage		–0.3		0.3 × V _{CCIO}	V
V _{OH}	High-level output voltage	I _{OUT} = –500 μA	0.9 × V _{CCIO}			V
V _{OL}	Low-level output voltage	I _{OUT} = 1,500 μA			0.1 × V _{CCIO}	V

Table 5–15. PCI-X Mode 1 Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage		3.0		3.6	V
V _{IH}	High-level input voltage		0.5 × V _{CCIO}		V _{CCIO} + 0.5	V
V _{IL}	Low-level input voltage		–0.30		0.35 × V _{CCIO}	V
V _{IPU}	Input pull-up voltage		0.7 × V _{CCIO}			V
V _{OH}	High-level output voltage	I _{OUT} = –500 μA	0.9 × V _{CCIO}			V
V _{OL}	Low-level output voltage	I _{OUT} = 1,500 μA			0.1 × V _{CCIO}	V

Table 5–16. SSTL-18 Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V _{REF}	Reference voltage		0.855	0.900	0.945	V
V _{TT}	Termination voltage		V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04	V
V _{IH} (DC)	High-level DC input voltage		V _{REF} + 0.125			V
V _{IL} (DC)	Low-level DC input voltage				V _{REF} – 0.125	V
V _{IH} (AC)	High-level AC input voltage		V _{REF} + 0.25			V
V _{IL} (AC)	Low-level AC input voltage				V _{REF} – 0.25	V
V _{OH}	High-level output voltage	I _{OH} = –6.7 mA (1)	V _{TT} + 0.475			V
V _{OL}	Low-level output voltage	I _{OL} = 6.7 mA (1)			V _{TT} – 0.475	V

Note to Table 5–16:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–17. SSTL-18 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Reference voltage		0.855	0.900	0.945	V
V_{TT}	Termination voltage		$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$	V
$V_{IH} (DC)$	High-level DC input voltage		$V_{REF} + 0.125$			V
$V_{IL} (DC)$	Low-level DC input voltage				$V_{REF} - 0.125$	V
$V_{IH} (AC)$	High-level AC input voltage		$V_{REF} + 0.25$			V
$V_{IL} (AC)$	Low-level AC input voltage				$V_{REF} - 0.25$	V
V_{OH}	High-level output voltage	$I_{OH} = -13.4 \text{ mA}$ (1)	$V_{CCIO} - 0.28$			V
V_{OL}	Low-level output voltage	$I_{OL} = 13.4 \text{ mA}$ (1)			0.28	V

Note to Table 5–17:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–18. SSTL-18 Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
$V_{SWING} (DC)$	DC differential input voltage		0.25			V
$V_X (AC)$	AC differential input cross point voltage		$(V_{CCIO}/2) - 0.175$		$(V_{CCIO}/2) + 0.175$	V
$V_{SWING} (AC)$	AC differential input voltage		0.5			V
V_{ISO}	Input clock signal offset voltage			$0.5 \times V_{CCIO}$		V
ΔV_{ISO}	Input clock signal offset voltage variation			± 200		mV
$V_{OX} (AC)$	AC differential cross point voltage		$(V_{CCIO}/2) - 0.125$		$(V_{CCIO}/2) + 0.125$	V

Table 5–19. SSTL-2 Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage		2.375	2.500	2.625	V
V _{TT}	Termination voltage		V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04	V
V _{REF}	Reference voltage		1.188	1.250	1.313	V
V _{IH} (DC)	High-level DC input voltage		V _{REF} + 0.18		3.00	V
V _{IL} (DC)	Low-level DC input voltage		–0.30		V _{REF} – 0.18	V
V _{IH} (AC)	High-level AC input voltage		V _{REF} + 0.35			V
V _{IL} (AC)	Low-level AC input voltage				V _{REF} – 0.35	V
V _{OH}	High-level output voltage	I _{OH} = –8.1 mA (1)	V _{TT} + 0.57			V
V _{OL}	Low-level output voltage	I _{OL} = 8.1 mA (1)			V _{TT} – 0.57	V

Note to Table 5–19:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–20. SSTL-2 Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage		2.375	2.500	2.625	V
V _{TT}	Termination voltage		V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04	V
V _{REF}	Reference voltage		1.188	1.250	1.313	V
V _{IH} (DC)	High-level DC input voltage		V _{REF} + 0.18		V _{CCIO} + 0.30	V
V _{IL} (DC)	Low-level DC input voltage		–0.30		V _{REF} – 0.18	V
V _{IH} (AC)	High-level AC input voltage		V _{REF} + 0.35			V
V _{IL} (AC)	Low-level AC input voltage				V _{REF} – 0.35	V
V _{OH}	High-level output voltage	I _{OH} = –16.4 mA (1)	V _{TT} + 0.76			V
V _{OL}	Low-level output voltage	I _{OL} = 16.4 mA (1)			V _{TT} – 0.76	V

Note to Table 5–20:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–21. SSTL-2 Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		2.375	2.500	2.625	V
V_{SWING} (DC)	DC differential input voltage		0.36			V
V_X (AC)	AC differential input cross point voltage		$(V_{CCIO}/2) - 0.2$		$(V_{CCIO}/2) + 0.2$	V
V_{SWING} (AC)	AC differential input voltage		0.7			V
V_{ISO}	Input clock signal offset voltage			$0.5 \times V_{CCIO}$		V
ΔV_{ISO}	Input clock signal offset voltage variation			± 200		mV
V_{OX} (AC)	AC differential output cross point voltage		$(V_{CCIO}/2) - 0.2$		$(V_{CCIO}/2) + 0.2$	V

Table 5–22. 1.2-V HSTL Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.14	1.20	1.26	V
V_{REF}	Reference voltage		$0.48 \times V_{CCIO}$	$0.50 \times V_{CCIO}$	$0.52 \times V_{CCIO}$	V
V_{IH} (DC)	High-level DC input voltage		$V_{REF} + 0.08$		$V_{CCIO} + 0.15$	V
V_{IL} (DC)	Low-level DC input voltage		-0.15		$V_{REF} - 0.08$	V
V_{IH} (AC)	High-level AC input voltage		$V_{REF} + 0.15$		$V_{CCIO} + 0.24$	V
V_{IL} (AC)	Low-level AC input voltage		-0.24		$V_{REF} - 0.15$	V
V_{OH}	High-level output voltage	$I_{OH} = 8 \text{ mA}$	$V_{REF} + 0.15$		$V_{CCIO} + 0.15$	V
V_{OL}	Low-level output voltage	$I_{OH} = -8 \text{ mA}$	-0.15		$V_{REF} - 0.15$	V

Table 5–23. 1.5-V HSTL Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage		1.425	1.500	1.575	V
V _{REF}	Input reference voltage		0.713	0.750	0.788	V
V _{TT}	Termination voltage		0.713	0.750	0.788	V
V _{IH} (DC)	DC high-level input voltage		V _{REF} + 0.1			V
V _{IL} (DC)	DC low-level input voltage		–0.3		V _{REF} – 0.1	V
V _{IH} (AC)	AC high-level input voltage		V _{REF} + 0.2			V
V _{IL} (AC)	AC low-level input voltage				V _{REF} – 0.2	V
V _{OH}	High-level output voltage	I _{OH} = 8 mA (1)	V _{CCIO} – 0.4			V
V _{OL}	Low-level output voltage	I _{OH} = –8 mA (1)			0.4	V

Note to Table 5–23:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–24. 1.5-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage		1.425	1.500	1.575	V
V _{REF}	Input reference voltage		0.713	0.750	0.788	V
V _{TT}	Termination voltage		0.713	0.750	0.788	V
V _{IH} (DC)	DC high-level input voltage		V _{REF} + 0.1			V
V _{IL} (DC)	DC low-level input voltage		–0.3		V _{REF} – 0.1	V
V _{IH} (AC)	AC high-level input voltage		V _{REF} + 0.2			V
V _{IL} (AC)	AC low-level input voltage				V _{REF} – 0.2	V
V _{OH}	High-level output voltage	I _{OH} = 16 mA (1)	V _{CCIO} – 0.4			V
V _{OL}	Low-level output voltage	I _{OH} = –16 mA (1)			0.4	V

Note to Table 5–24:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–25. 1.5-V HSTL Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage		1.425	1.500	1.575	V
V_{DIF} (DC)	DC input differential voltage		0.2			V
V_{CM} (DC)	DC common mode input voltage		0.68		0.90	V
V_{DIF} (AC)	AC differential input voltage		0.4			V
V_{OX} (AC)	AC differential cross point voltage		0.68		0.90	V

Table 5–26. 1.8-V HSTL Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Input reference voltage		0.85	0.90	0.95	V
V_{TT}	Termination voltage		0.85	0.90	0.95	V
V_{IH} (DC)	DC high-level input voltage		$V_{REF} + 0.1$			V
V_{IL} (DC)	DC low-level input voltage		-0.3		$V_{REF} - 0.1$	V
V_{IH} (AC)	AC high-level input voltage		$V_{REF} + 0.2$			V
V_{IL} (AC)	AC low-level input voltage				$V_{REF} - 0.2$	V
V_{OH}	High-level output voltage	$I_{OH} = 8 \text{ mA}$ (1)	$V_{CCIO} - 0.4$			V
V_{OL}	Low-level output voltage	$I_{OH} = -8 \text{ mA}$ (1)			0.4	V

Note to Table 5–26:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–27. 1.8-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.71	1.80	1.89	V
V_{REF}	Input reference voltage		0.85	0.90	0.95	V
V_{TT}	Termination voltage		0.85	0.90	0.95	V
V_{IH} (DC)	DC high-level input voltage		$V_{REF} + 0.1$			V
V_{IL} (DC)	DC low-level input voltage		-0.3		$V_{REF} - 0.1$	V
V_{IH} (AC)	AC high-level input voltage		$V_{REF} + 0.2$			V
V_{IL} (AC)	AC low-level input voltage				$V_{REF} - 0.2$	V
V_{OH}	High-level output voltage	$I_{OH} = 16 \text{ mA}$ (1)	$V_{CCIO} - 0.4$			V
V_{OL}	Low-level output voltage	$I_{OH} = -16 \text{ mA}$ (1)			0.4	V

Note to Table 5–27:

- (1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–28. 1.8-V HSTL Class I & II Differential Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	I/O supply voltage		1.71	1.80	1.89	V
V_{DIF} (DC)	DC input differential voltage		0.2		$V_{CCIO} + 0.6 \text{ V}$	V
V_{CM} (DC)	DC common mode input voltage		0.78		1.12	V
V_{DIF} (AC)	AC differential input voltage		0.4		$V_{CCIO} + 0.6 \text{ V}$	V
V_{OX} (AC)	AC differential cross point voltage		0.68		0.90	V

Bus Hold Specifications

Table 5–29 shows the Stratix II device family bus hold specifications.

Parameter	Conditions	V_{CCIO} Level										Unit
		1.2 V		1.5 V		1.8 V		2.5 V		3.3 V		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	$V_{IN} > V_{IL}$ (maximum)	22.5		25.0		30.0		50.0		70.0		μA
High sustaining current	$V_{IN} < V_{IH}$ (minimum)	-22.5		-25.0		-30.0		-50.0		-70.0		μA
Low overdrive current	$0\text{ V} < V_{IN} < V_{CCIO}$		120		160		200		300		500	μA
High overdrive current	$0\text{ V} < V_{IN} < V_{CCIO}$		-120		-160		-200		-300		-500	μA
Bus-hold trip point		0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination Specifications

Tables 5–30 and 5–31 define the specification for internal termination resistance tolerance when using series or differential on-chip termination.

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
25- Ω R_S 3.3/2.5	Internal series termination with calibration (25- Ω setting)	$V_{CCIO} = 3.3/2.5\text{ V}$	± 5	± 10	%
	Internal series termination without calibration (25- Ω setting)	$V_{CCIO} = 3.3/2.5\text{ V}$	± 30	± 30	%

Table 5–30. Series On-Chip Termination Specification for Top & Bottom I/O Banks (Part 2 of 2)
Notes (1), 2

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
50-Ω R _S 3.3/2.5	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 3.3/2.5 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 3.3/2.5 V	±30	±30	%
50-Ω R _T 2.5	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±30	±30	%
25-Ω R _S 1.8	Internal series termination with calibration (25-Ω setting)	V _{CCIO} = 1.8 V	±5	±10	%
	Internal series termination without calibration (25-Ω setting)	V _{CCIO} = 1.8 V	±30	±30	%
50-Ω R _S 1.8	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±30	±30	%
50-Ω R _T 1.8	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±10	±15	%
50-Ω R _S 1.5	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±8	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±36	±36	%
50-Ω R _T 1.5	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±10	±15	%
50-Ω R _S 1.2	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 1.2 V	±8	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.2 V	±50	±50	%
50-Ω R _T 1.2	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.2 V	±10	±15	%

Notes for Table 5–30:

- (1) The resistance tolerances for calibrated SOCT and POCT are for the moment of calibration. If the temperature or voltage changes over time, the tolerance may also change.
- (2) On-chip parallel termination with calibration is only supported for input pins.

Table 5–31. Series & Differential On-Chip Termination Specification for Left & Right I/O Banks

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
25-Ω R _S 3.3/2.5	Internal series termination without calibration (25-Ω setting)	V _{CCIO} = 3.3/2.5 V	±30	±30	%
50-Ω R _S 3.3/2.5/1.8	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 3.3/2.5/1.8 V	±30	±30	%
50-Ω R _S 1.5	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±36	±36	%
R _D	Internal differential termination for LVDS or HyperTransport technology (100-Ω setting)	V _{CCIO} = 2.5 V	±20	±25	%

Pin Capacitance

Table 5–32 shows the Stratix II device family pin capacitance.

Table 5–32. Stratix II Device Capacitance Note (1)

Symbol	Parameter	Typical	Unit
C _{IOTB}	Input capacitance on I/O pins in I/O banks 3, 4, 7, and 8.	5.0	pF
C _{IOLR}	Input capacitance on I/O pins in I/O banks 1, 2, 5, and 6, including high-speed differential receiver and transmitter pins.	6.1	pF
C _{CLKTB}	Input capacitance on top/bottom clock input pins: CLK [4 . . 7] and CLK [12 . . 15].	6.0	pF
C _{CLKLR}	Input capacitance on left/right clock inputs: CLK0, CLK2, CLK8, CLK10.	6.1	pF
C _{CLKLR+}	Input capacitance on left/right clock inputs: CLK1, CLK3, CLK9, and CLK11.	3.3	pF
C _{OUTFB}	Input capacitance on dual-purpose clock output/feedback pins in PLL banks 9, 10, 11, and 12.	6.7	pF

Note to Table 5–32:

- (1) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5pF

Power Consumption

Altera® offers two ways to calculate power for a design: the Excel-based PowerPlay Early Power Estimator power calculator and the Quartus® II PowerPlay Power Analyzer feature.

The interactive Excel-based PowerPlay Early Power Estimator is typically used prior to designing the FPGA in order to get an estimate of device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after place-and-route is complete. The Power Analyzer can apply a combination of user-entered, simulation-derived and estimated signal activities which, combined with detailed circuit models, can yield very accurate power estimates.

In both cases, these calculations should only be used as an estimation of power, not as a specification.



For more information about PowerPlay tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Early Power Estimator* and *PowerPlay Power Analyzer* chapters in volume 3 of the *Quartus II Handbook*.

The PowerPlay Early Power Estimator is available on the Altera web site at www.altera.com. See [Table 5-4 on page 5-3](#) for typical I_{CC} standby specifications.

Timing Model

The DirectDrive™ technology and MultiTrack™ interconnect ensure predictable performance, accurate simulation, and accurate timing analysis across all Stratix II device densities and speed grades. This section describes and specifies the performance, internal timing, external timing, and PLL, high-speed I/O, external memory interface, and JTAG timing specifications.

All specifications are representative of worst-case supply voltage and junction temperature conditions.



The timing numbers listed in the tables of this section are extracted from the Quartus II software version 5.0 SP1.

Preliminary & Final Timing

Timing models can have either preliminary or final status. The Quartus II software issues an informational message during the design compilation if the timing models are preliminary. [Table 5-33](#) shows the status of the Stratix II device timing models.

Preliminary status means the timing model is subject to change. Initially, timing numbers are created using simulation results, process data, and other known parameters. These tests are used to make the preliminary numbers as close to the actual timing parameters as possible.

Final timing numbers are based on actual device operation and testing. These numbers reflect the actual performance of the device under worst-case voltage and junction temperature conditions.

Table 5–33. Stratix II Device Timing Model Status

Device	Preliminary	Final
EP2S15		✓
EP2S30		✓
EP2S60		✓
EP2S90		✓
EP2S130		✓
EP2S180		✓

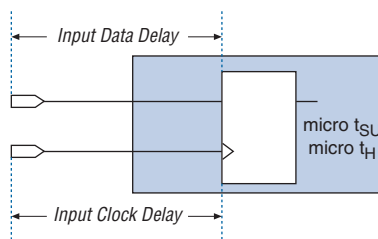
I/O Timing Measurement Methodology

Altera characterizes timing delays at the worst-case process, minimum voltage, and maximum temperature for input register setup time (t_{SU}) and hold time (t_H). The Quartus II software uses the following equations to calculate t_{SU} and t_H timing for Stratix II devices input signals.

$$t_{SU} = + \text{data delay from input pin to input register} \\ + \text{micro setup time of the input register} \\ - \text{clock delay from input pin to input register}$$

$$t_H = - \text{data delay from input pin to input register} \\ + \text{micro hold time of the input register} \\ + \text{clock delay from input pin to input register}$$

Figure 5–3 shows the setup and hold timing diagram for input registers.

Figure 5–3. Input Register Setup & Hold Timing Diagram

For output timing, different I/O standards require different baseline loading techniques for reporting timing delays. Altera characterizes timing delays with the required termination for each I/O standard and with 0 pF (except for PCI and PCI-X which use 10 pF) loading and the timing is specified up to the output pin of the FPGA device. The Quartus II software calculates the I/O timing for each I/O standard with a default baseline loading as specified by the I/O standards.

The following measurements are made during device characterization. Altera measures clock-to-output delays (t_{CO}) at worst-case process, minimum voltage, and maximum temperature (PVT) for default loading conditions shown in Table 5–34. Use the following equations to calculate clock pin to output pin timing for Stratix II devices.

$$t_{CO} \text{ from clock pin to I/O pin} = \text{delay from clock pad to I/O output register} + \text{IOE output register clock-to-output delay} + \text{delay from output register to output pin} + \text{I/O output delay}$$

$$t_{xz}/t_{zx} \text{ from clock pin to I/O pin} = \text{delay from clock pad to I/O output register} + \text{IOE output register clock-to-output delay} + \text{delay from output register to output pin} + \text{I/O output delay} + \text{output enable pin delay}$$

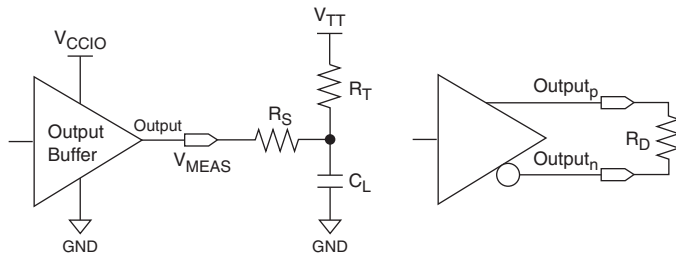
Simulation using IBIS models is required to determine the delays on the PCB traces in addition to the output pin delay timing reported by the Quartus II software and the timing model in the device handbook.

1. Simulate the output driver of choice into the generalized test setup, using values from Table 5–34.
2. Record the time to V_{MEAS} .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.

4. Record the time to V_{MEAS} .
5. Compare the results of steps 2 and 4. The increase or decrease in delay should be added to or subtracted from the I/O Standard Output Adder delays to yield the actual worst-case propagation delay (clock-to-output) of the PCB trace.

The Quartus II software reports the timing with the conditions shown in [Table 5–34](#) using the above equation. [Figure 5–4](#) shows the model of the circuit that is represented by the output timing of the Quartus II software.

Figure 5–4. Output Delay Timing Reporting Setup Modeled by Quartus II



Notes to [Figure 5–4](#):

- (1) Output pin timing is reported at the output pin of the FPGA device. Additional delays for loading and board trace delay need to be accounted for with IBIS model simulations.
- (2) V_{CCPD} is 3.085 V unless otherwise specified.
- (3) V_{CCINT} is 1.12 V unless otherwise specified.

[Figures 5–5](#) and [5–6](#) show the measurement setup for output disable and output enable timing.

I/O Standard	Loading and Termination						Measurement Point
	R_S (Ω)	R_D (Ω)	R_T (Ω)	V_{CCIO} (V)	V_{TT} (V)	C_L (pF)	V_{MEAS} (V)
LVTTL (4)				3.135		0	1.5675
LVC MOS (4)				3.135		0	1.5675
2.5 V (4)				2.375		0	1.1875
1.8 V (4)				1.710		0	0.855
1.5 V (4)				1.425		0	0.7125
PCI (5)				2.970		10	1.485
PCI-X (5)				2.970		10	1.485
SSTL-2 Class I	25		50	2.325	1.123	0	1.1625
SSTL-2 Class II	25		25	2.325	1.123	0	1.1625
SSTL-18 Class I	25		50	1.660	0.790	0	0.83
SSTL-18 Class II	25		25	1.660	0.790	0	0.83
1.8-V HSTL Class I	50		50	1.660	0.790	0	0.83
1.8-V HSTL Class II	25		25	1.660	0.790	0	0.83
1.5-V HSTL Class I	50		50	1.375	0.648	0	0.6875
1.5-V HSTL Class II			25	1.375	0.648	0	0.6875
1.2-V HSTL with OCT	50			1.140		0	0.570
Differential SSTL-2 Class I	50		50	2.325	1.123	0	1.1625
Differential SSTL-2 Class II	25		25	2.325	1.123	0	1.1625
Differential SSTL-18 Class I	50		50	1.660	0.790	0	0.83
Differential SSTL-18 Class II	25		25	1.660	0.790	0	0.83
1.5-V Differential HSTL Class I	50		50	1.375	0.648	0	0.6875
1.5-V Differential HSTL Class II			25	1.375	0.648	0	0.6875
1.8-V Differential HSTL Class I	50		50	1.660	0.790	0	0.83
1.8-V Differential HSTL Class II	25		25	1.660	0.790	0	0.83
LVDS		100		2.325		0	1.1625
HyperTransport		100		2.325		0	1.1625
LVPECL		100		3.135		0	1.5675

Notes to Table 5–34:

- (1) Input measurement point at internal node is $0.5 \times V_{CCINT}$.
- (2) Output measuring point for V_{MEAS} at buffer output is $0.5 \times V_{CCIO}$.
- (3) Input stimulus edge rate is 0 to V_{CC} in 0.2 ns (internal signal) from the driver preceding the I/O buffer.
- (4) Less than 50-mV ripple on V_{CCIO} and V_{CCPD} , $V_{CCINT} = 1.15$ V with less than 30-mV ripple
- (5) $V_{CCPD} = 2.97$ V, less than 50-mV ripple on V_{CCIO} and V_{CCPD} , $V_{CCINT} = 1.15$ V

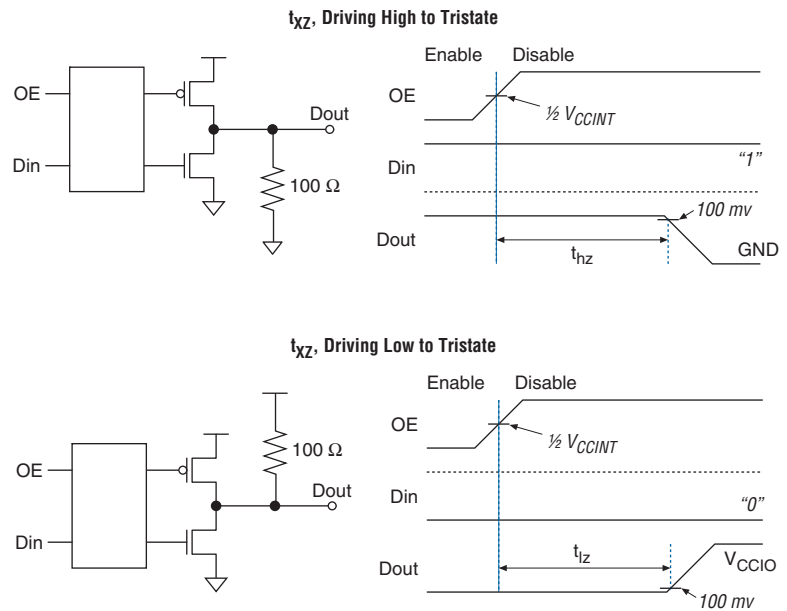
Figure 5-5. Measurement Setup for t_{xz} Note (1)**Note to Figure 5-5:**(1) V_{CCIINT} is 1.12 V for this measurement.

Figure 5–6. Measurement Setup for t_{zx}

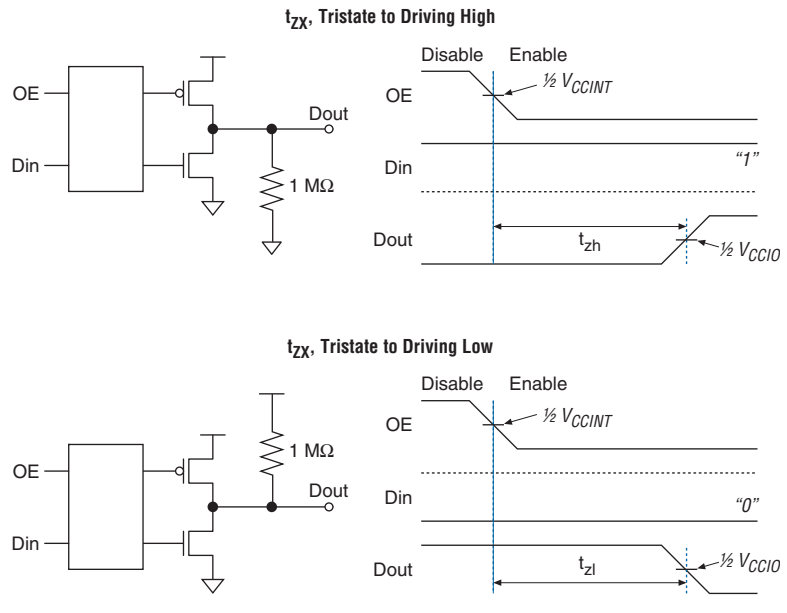


Table 5–35 specifies the input timing measurement setup.

I/O Standard	Measurement Conditions			Measurement Point
	V_{CCIO} (V)	V_{REF} (V)	Edge Rate (ns)	V_{MEAS} (V)
LVTTTL (5)	3.135		3.135	1.5675
LVC MOS (5)	3.135		3.135	1.5675
2.5 V (5)	2.375		2.375	1.1875
1.8 V (5)	1.710		1.710	0.855
1.5 V (5)	1.425		1.425	0.7125
PCI (6)	2.970		2.970	1.485
PCI-X (6)	2.970		2.970	1.485
SSTL-2 Class I	2.325	1.163	2.325	1.1625
SSTL-2 Class II	2.325	1.163	2.325	1.1625
SSTL-18 Class I	1.660	0.830	1.660	0.83
SSTL-18 Class II	1.660	0.830	1.660	0.83
1.8-V HSTL Class I	1.660	0.830	1.660	0.83

Table 5–35. Timing Measurement Methodology for Input Pins (Part 2 of 2) Notes (1)–(4)

I/O Standard	Measurement Conditions			Measurement Point
	V _{CCIO} (V)	V _{REF} (V)	Edge Rate (ns)	V _{MEAS} (V)
1.8-V HSTL Class II	1.660	0.830	1.660	0.83
1.5-V HSTL Class I	1.375	0.688	1.375	0.6875
1.5-V HSTL Class II	1.375	0.688	1.375	0.6875
1.2-V HSTL with OCT	1.140	0.570	1.140	0.570
Differential SSTL-2 Class I	2.325	1.163	2.325	1.1625
Differential SSTL-2 Class II	2.325	1.163	2.325	1.1625
Differential SSTL-18 Class I	1.660	0.830	1.660	0.83
Differential SSTL-18 Class II	1.660	0.830	1.660	0.83
1.5-V Differential HSTL Class I	1.375	0.688	1.375	0.6875
1.5-V Differential HSTL Class II	1.375	0.688	1.375	0.6875
1.8-V Differential HSTL Class I	1.660	0.830	1.660	0.83
1.8-V Differential HSTL Class II	1.660	0.830	1.660	0.83
LVDS	2.325		0.100	1.1625
HyperTransport	2.325		0.400	1.1625
LVPECL	3.135		0.100	1.5675

Notes to Table 5–35:

- (1) Input buffer sees no load at buffer input.
- (2) Input measuring point at buffer input is $0.5 \times V_{CCIO}$.
- (3) Output measuring point is $0.5 \times V_{CC}$ at internal node.
- (4) Input edge rate is 1 V/ns.
- (5) Less than 50-mV ripple on V_{CCIO} and V_{CCPD}, V_{CCINT} = 1.15 V with less than 30-mV ripple
- (6) V_{CCPD} = 2.97 V, less than 50-mV ripple on V_{CCIO} and V_{CCPD}, V_{CCINT} = 1.15 V

Performance

Table 5–36 shows Stratix II performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM), or MegaCore® functions for the finite impulse response (FIR) and fast Fourier transform (FFT) designs.



The performance numbers in Table 5–36 are extracted from the Quartus II software version 5.1 SP1.

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
LE	16-to-1 multiplexer (4)	21	0	0	654.87	625.0	523.83	460.4	MHz
	32-to-1 multiplexer (4)	38	0	0	519.21	473.26	464.25	384.17	MHz
	16-bit counter	16	0	0	566.57	538.79	489.23	421.05	MHz
	64-bit counter	64	0	0	244.31	232.07	209.11	181.38	MHz
TriMatrix Memory M512 block	Simple dual-port RAM 32 x 18 bit	0	1	0	500.00	476.19	434.02	373.13	MHz
	FIFO 32 x 18 bit	22	1	0	500.00	476.19	434.78	373.13	MHz
TriMatrix Memory M4K block	Simple dual-port RAM 128 x 36 bit (8)	0	1	0	540.54	515.46	469.48	401.60	MHz
	True dual-port RAM 128 x 18 bit (8)	0	1	0	540.54	515.46	469.48	401.60	MHz
	FIFO 128 x 36 bit	22	1	0	530.22	499.00	469.48	401.60	MHz
	Simple dual-port RAM 128 x 36 bit (9)	0	1	0	475.28	453.30	413.22	354.10	MHz
	True dual-port RAM 128 x 18 bit (9)	0	1	0	475.28	453.30	413.22	354.10	MHz

Table 5–36. Stratix II Performance Notes (Part 2 of 6) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
TriMatrix Memory M-RAM block	Single port RAM 4K × 144 bit	0	1	0	349.65	333.33	303.95	261.09	MHz
	Simple dual-port RAM 4K × 144 bit	0	1	0	420.16	400.00	364.96	313.47	MHz
	True dual-port RAM 4K × 144 bit	0	1	0	349.65	333.33	303.95	261.09	MHz
	Single port RAM 8K × 72 bit	0	1	0	354.60	337.83	307.69	263.85	MHz
	Simple dual-port RAM 8K × 72 bit	0	1	0	420.16	400.00	364.96	313.47	MHz
	True dual-port RAM 8K × 72 bit	0	1	0	349.65	333.33	303.95	261.09	MHz
	Single port RAM 16K × 36 bit	0	1	0	364.96	347.22	317.46	271.73	MHz
	Simple dual-port RAM 16K × 36 bit	0	1	0	420.16	400.00	364.96	313.47	MHz
	True dual-port RAM 16K × 36 bit	0	1	0	359.71	342.46	313.47	268.09	MHz
	Single port RAM 32K × 18 bit	0	1	0	364.96	347.22	317.46	271.73	MHz
	Simple dual-port RAM 32K × 18 bit	0	1	0	420.16	400.0	364.96	313.47	MHz
	True dual-port RAM 32K × 18 bit	0	1	0	359.71	342.46	313.47	268.09	MHz
	Single port RAM 64K × 9 bit	0	1	0	364.96	347.22	317.46	271.73	MHz
	Simple dual-port RAM 64K × 9 bit	0	1	0	420.16	400.0	364.96	313.47	MHz
	True dual-port RAM 64K × 9 bit	0	1	0	359.71	342.46	313.47	268.09	MHz

Table 5–36. Stratix II Performance Notes (Part 3 of 6) <i>Note (1)</i>									
Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
DSP block	9 × 9-bit multiplier (5)	0	0	1	430.29	409.16	373.13	320.10	MHz
	18 × 18-bit multiplier (5)	0	0	1	410.17	390.01	356.12	305.06	MHz
	18 × 18-bit multiplier (7)	0	0	1	450.04	428.08	391.23	335.12	MHz
	36 × 36-bit multiplier (5)	0	0	1	250.00	238.15	217.48	186.60	MHz
	36 × 36-bit multiplier (6)	0	0	1	410.17	390.01	356.12	305.06	MHz
	18-bit, four-tap FIR filter	0	0	1	410.17	390.01	356.12	305.06	MHz
Larger designs	8-bit, 16-tap parallel FIR filter	58	0	4	259.06	240.61	217.15	185.01	MHz
	8-bit, 1024-point, streaming, three multipliers and five adders FFT function	2976	22	9	398.72	364.03	355.23	306.37	MHz
	8-bit, 1024-point, streaming, four multipliers and two adders FFT function	2781	22	12	398.56	409.16	347.22	311.13	MHz
	8-bit, 1024-point, single output, one parallel FFT engine, burst, three multipliers and five adders FFT function	984	5	3	425.17	365.76	346.98	292.39	MHz
	8-bit, 1024-point, single output, one parallel FFT engine, burst, four multipliers and two adders FFT function	919	5	4	427.53	378.78	357.14	307.59	MHz

Table 5–36. Stratix II Performance Notes (Part 4 of 6) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, single output, two parallel FFT engines, burst, three multiplier and five adders FFT function	1725	10	6	430.29	401.92	373.13	319.08	MHz
	8-bit, 1024-point, single output, two parallel FFT engines, burst, four multipliers and two adders FFT function	1594	10	8	422.65	407.33	373.13	329.10	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, burst, three multipliers and five adders FFT function	2361	10	9	315.45	342.81	325.73	284.25	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, burst, four multipliers and two adders FFT function	2165	10	12	373.13	369.54	317.96	256.14	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, burst, three multipliers and five adders FFT function	3996	14	18	378.50	367.10	332.33	288.68	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, burst, four multipliers and two adders FFT function	3604	14	24	391.38	361.14	340.25	280.89	MHz

Table 5–36. Stratix II Performance Notes (Part 5 of 6) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, quadrant output, four parallel FFT engines, burst, three multipliers and five adders FFT function	6850	28	36	334.11	345.66	308.54	276.31	MHz
	8-bit, 1024-point, quadrant output, four parallel FFT engines, burst, four multipliers two adders FFT function	6067	28	48	367.91	349.04	327.33	268.24	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, buffered burst, three multipliers and adders FFT function	2730	18	9	387.44	388.34	364.56	306.84	MHz
	8-bit, 1024-point, quadrant output, one parallel FFT engine, buffered burst, four multipliers and two adders FFT function	2534	18	12	419.28	369.66	364.96	307.88	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, buffered burst, three multipliers five adders FFT function	4358	30	18	396.51	378.07	340.13	291.29	MHz
	8-bit, 1024-point, quadrant output, two parallel FFT engines, buffered burst four multipliers and two adders FFT function	3966	30	24	389.71	398.08	356.53	280.74	MHz

Table 5–36. Stratix II Performance Notes (Part 6 of 6) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, three multipliers five adders FFT function	7385	60	36	359.58	352.98	312.01	278.00	MHz
	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, four multipliers and two adders FFT function	6601	60	48	371.88	355.74	327.86	277.62	MHz

Notes for Table 5–36:

- (1) These design performance numbers were obtained using the Quartus II software version 5.0 SP1.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) This application uses registered inputs and outputs.
- (5) This application uses registered multiplier input and output stages within the DSP block.
- (6) This application uses registered multiplier input, pipeline, and output stages within the DSP block.
- (7) This application uses registered multiplier input with output of the multiplier stage feeding the accumulator or subtractor within the DSP block.
- (8) This application uses the same clock source that is globally routed and connected to ports A and B.
- (9) This application uses locally routed clocks or differently sourced clocks for ports A and B.

Internal Timing Parameters

See Tables 5–37 through 5–42 for internal timing parameters.

Symbol	Parameter	-3 Speed Grade (1)		-3 Speed Grade (2)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (3)	Max	Min (3)	Max	Min (4)	Max	Min (3)	Max	
t_{SU}	LE register setup time before clock	90		95		104 104		121		ps
t_H	LE register hold time after clock	149		157		172 172		200		ps
t_{CO}	LE register clock-to-output delay	62	94	62	99	59 62	109	62	127	ps
t_{CLR}	Minimum clear pulse width	204		214		234 234		273		ps
t_{PRE}	Minimum preset pulse width	204		214		234 234		273		ps
t_{CLKL}	Minimum clock low time	612		642		703 703		820		ps
t_{CLKH}	Minimum clock high time	612		642		703 703		820		ps
t_{LUT}		162	378	162	397	162 170	435	162	507	ps
t_{ADDER}		354	619	354	650	354 372	712	354	829	ps

Notes to Table 5–37:

- (1) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (2) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (3) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (4) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–38. IOE Internal Timing Microparameters

Symbol	Parameter	-3 Speed Grade (1)		-3 Speed Grade (2)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (3)	Max	Min (3)	Max	Min (4)	Max	Min (3)	Max	
t_{SU}	IOE input and output register setup time before clock	122		128		140 140		163		ps
t_H	IOE input and output register hold time after clock	72		75		82 82		96		ps
t_{CO}	IOE input and output register clock-to-output delay	101	169	101	177	97 101	194	101	226	ps
$t_{PIN2COMBOUT_R}$	Row input pin to IOE combinational output	410	760	410	798	391 410	873	410	1,018	ps
$t_{PIN2COMBOUT_C}$	Column input pin to IOE combinational output	428	787	428	825	408 428	904	428	1,054	ps
$t_{COMBIN2PIN_R}$	Row IOE data input to combinational output pin	1,101	2,026	1,101	2,127	1,049 1,101	2,329	1,101	2,439	ps
$t_{COMBIN2PIN_C}$	Column IOE data input to combinational output pin	991	1,854	991	1,946	944 991	2,131	991	2,246	ps
t_{CLR}	Minimum clear pulse width	200		210		229 229		268		ps
t_{PRE}	Minimum preset pulse width	200		210		229 229		268		ps
t_{CLKL}	Minimum clock low time	600		630		690 690		804		ps
t_{CLKH}	Minimum clock high time	600		630		690 690		804		ps

Notes to Table 5–38:

- (1) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (2) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (3) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (4) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–39. DSP Block Internal Timing Microparameters (Part 1 of 2)

Symbol	Parameter	-3 Speed Grade (1)		-3 Speed Grade (2)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (3)	Max	Min (3)	Max	Min (4)	Max	Min (3)	Max	
t_{SU}	Input, pipeline, and output register setup time before clock	50		52		57 57		67		ps
t_H	Input, pipeline, and output register hold time after clock	180		189		206 206		241		ps
t_{CO}	Input, pipeline, and output register clock-to-output delay	0	0	0	0	0 0	0	0	0	ps
$t_{INREG2PIPE9}$	Input register to DSP block pipeline register in 9 × 9-bit mode	1,312	2,030	1,312	2,030	1,250 1,312	2,334	1,312	2,720	ps
$t_{INREG2PIPE18}$	Input register to DSP block pipeline register in 18 × 18-bit mode	1,302	2,010	1,302	2,110	1,240 1,302	2,311	1,302	2,693	ps
$t_{INREG2PIPE36}$	Input register to DSP block pipeline register in 36 × 36-bit mode	1,302	2,010	1,302	2,110	1,240 1,302	2,311	1,302	2,693	ps
$t_{PIPE2OUTREG2ADD}$	DSP block pipeline register to output register delay in two-multipliers adder mode	924	1,450	924	1,522	880 924	1,667	924	1,943	ps
$t_{PIPE2OUTREG4ADD}$	DSP block pipeline register to output register delay in four-multipliers adder mode	1,134	1,850	1,134	1,942	1,080 1,134	2,127	1,134	2,479	ps
t_{PD9}	Combinational input to output delay for 9 × 9	2,100	2,880	2,100	3,024	2,000 2,100	3,312	2,100	3,859	ps
t_{PD18}	Combinational input to output delay for 18 × 18	2,110	2,990	2,110	3,139	2,010 2,110	3,438	2,110	4,006	ps
t_{PD36}	Combinational input to output delay for 36 × 36	2,939	4,450	2,939	4,672	2,800 2,939	5,117	2,939	5,962	ps
t_{CLR}	Minimum clear pulse width	2,212		2,322		2,543 2,543		2,964		ps

Table 5–39. DSP Block Internal Timing Microparameters (Part 2 of 2)

Symbol	Parameter	-3 Speed Grade (1)		-3 Speed Grade (2)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (3)	Max	Min (3)	Max	Min (4)	Max	Min (3)	Max	
t_{CLKL}	Minimum clock low time	1,190		1,249		1,368 1,368		1,594		ps
t_{CLKH}	Minimum clock high time	1,190		1,249		1,368 1,368		1,594		ps

Notes to Table 5–39:

- (1) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (2) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (3) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (4) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–40. M512 Block Internal Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{M512RC}	Synchronous read cycle time	2,089	2,318	2,089	2,433	1,989 2,089	2,664	2,089	3,104	ps
$t_{M512WERESU}$	Write or read enable setup time before clock	22		23		25 25		29		ps
$t_{M512WEREH}$	Write or read enable hold time after clock	203		213		233 233		272		ps
$t_{M512DATASU}$	Data setup time before clock	22		23		25 25		29		ps
$t_{M512DATAH}$	Data hold time after clock	203		213		233 233		272		ps
$t_{M512WADDRSU}$	Write address setup time before clock	22		23		25 25		29		ps
$t_{M512WADDRH}$	Write address hold time after clock	203		213		233 233		272		ps
$t_{M512RADDRSU}$	Read address setup time before clock	22		23		25 25		29		ps
$t_{M512RADDRH}$	Read address hold time after clock	203		213		233 233		272		ps

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
$t_{M512DATAO1}$	Clock-to-output delay when using output registers	298	478	298	501	284 298	548	298	640	ps
$t_{M512DATAO2}$	Clock-to-output delay without output registers	2,102	2,345	2,102	2,461	2,003 2,102	2,695	2,102	3,141	ps
$t_{M512CLKL}$	Minimum clock low time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLKH}$	Minimum clock high time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLR}$	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–40:

- (1) F_{MAX} of M512 block obtained using the Quartus II software does not necessarily equal to $1/T_{M512RC}$.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{M4KRRC}	Synchronous read cycle time	1,462	2,240	1,462	2,351	1,393 1,462	2,575	1,462	3,000	ps
$t_{M4KWERESU}$	Write or read enable setup time before clock	22		23		25 25		29		ps
$t_{M4KWEREH}$	Write or read enable hold time after clock	203		213		233 233		272		ps
$t_{M4KBESU}$	Byte enable setup time before clock	22		23		25 25		29		ps
t_{M4KBEH}	Byte enable hold time after clock	203		213		233 233		272		ps

Table 5–41. M4K Block Internal Timing Microparameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
$t_{M4KDATAASU}$	A port data setup time before clock	22		23		25 25		29		ps
$t_{M4KDATAAH}$	A port data hold time after clock	203		213		233 233		272		ps
$t_{M4KADDRASU}$	A port address setup time before clock	22		23		25 25		29		ps
$t_{M4KADDRAH}$	A port address hold time after clock	203		213		233 233		272		ps
$t_{M4KDATABSU}$	B port data setup time before clock	22		23		25 25		29		ps
$t_{M4KDATABH}$	B port data hold time after clock	203		213		233 233		272		ps
$t_{M4KRADDRBSU}$	B port address setup time before clock	22		23		25 25		29		ps
$t_{M4KRADDRBH}$	B port address hold time after clock	203		213		233 233		272		ps
$t_{M4KDATA CO1}$	Clock-to-output delay when using output registers	334	524	334	549	319 334	601	334	701	ps
$t_{M4KDATA CO2}$ (6)	Clock-to-output delay without output registers	1,616	2,453	1,616	2,574	1,540 1,616	2,820	1,616	3,286	ps
$t_{M4KCLKH}$	Minimum clock high time	1,250		1,312		1,437 1,437		1,675		ps
$t_{M4KCLKL}$	Minimum clock low time	1,250		1,312		1,437 1,437		1,675		ps
t_{M4KCLR}	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–41:

- (1) F_{MAX} of M4K Block obtained using the Quartus II software does not necessarily equal to $1/TM4KRC$.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.
- (6) Numbers apply to unpacked memory modes, true dual-port memory modes, and simple dual-port memory modes that use locally routed or non-identical sources for the A and B port registers.

Table 5–42. M-RAM Block Internal Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{MEGARC}	Synchronous read cycle time	1,866	2,774	1,866	2,911	1,777 1,866	3,189	1,777 1,866	3,716	ps
$t_{MEGAWERESU}$	Write or read enable setup time before clock	144		151		165 165		192		ps
$t_{MEGAWEREH}$	Write or read enable hold time after clock	39		40		44 44		52		ps
$t_{MEGABESU}$	Byte enable setup time before clock	50		52		57 57		67		ps
$t_{MEGABEH}$	Byte enable hold time after clock	39		40		44 44		52		ps
$t_{MEGADATAASU}$	A port data setup time before clock	50		52		57 57		67		ps
$t_{MEGADATAAH}$	A port data hold time after clock	243		255		279 279		325		ps
$t_{MEGAADDRASU}$	A port address setup time before clock	589		618		677 677		789		ps
$t_{MEGAADDRAH}$	A port address hold time after clock	241		253		277 277		322		ps
$t_{MEGADATABSU}$	B port setup time before clock	50		52		57 57		67		ps
$t_{MEGADATABH}$	B port hold time after clock	243		255		279 279		325		ps
$t_{MEGAADDRBSU}$	B port address setup time before clock	589		618		677 677		789		ps
$t_{MEGAADDRBH}$	B port address hold time after clock	241		253		277 277		322		ps
$t_{MEGADATACO1}$	Clock-to-output delay when using output registers	480	715	480	749	457 480	821	480	957	ps
$t_{MEGADATACO2}$	Clock-to-output delay without output registers	1,950	2,899	1,950	3,042	1,857 1,950	3,332	1,950	3,884	ps
$t_{MEGACLKL}$	Minimum clock low time	1,250		1,312		1,437 1,437		1,675		ps

Table 5–42. M-RAM Block Internal Timing Microparameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{MEGACLKH}	Minimum clock high time	1,250		1,312		1,437 1,437		1,675		ps
t_{MEGACLRL}	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–42:

- (1) F_{MAX} of M-RAM Block obtained using the Quartus II software does not necessarily equal to $1/\text{TMEGARC}$.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
- (4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
- (5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Stratix II Clock Timing Parameters

See Tables 5–43 through 5–67 for Stratix II clock timing parameters.

Table 5–43. Stratix II Clock Timing Parameters

Symbol	Parameter
t_{CIN}	Delay from clock pad to I/O input register
t_{COUT}	Delay from clock pad to I/O output register
t_{PLLCIN}	Delay from PLL <code>inclk</code> pad to I/O input register
t_{PLLCOUT}	Delay from PLL <code>inclk</code> pad to I/O output register

EP2S15 Clock Timing Parameters

Tables 5–44 through 5–47 show the maximum clock timing parameters for EP2S15 devices.

Table 5–44. EP2S15 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.445	1.512	2.487	2.848	3.309	ns
t_{COUT}	1.288	1.347	2.245	2.570	2.985	ns
$t_{PLL\,CIN}$	0.104	0.102	0.336	0.373	0.424	ns
$t_{PLL\,COUT}$	-0.053	-0.063	0.094	0.095	0.1	ns

Table 5–45. EP2S15 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.419	1.487	2.456	2.813	3.273	ns
t_{COUT}	1.262	1.322	2.214	2.535	2.949	ns
$t_{PLL\,CIN}$	0.094	0.092	0.326	0.363	0.414	ns
$t_{PLL\,COUT}$	-0.063	-0.073	0.084	0.085	0.09	ns

Table 5–46. EP2S15 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.232	1.288	2.144	2.454	2.848	ns
t_{COUT}	1.237	1.293	2.140	2.450	2.843	ns
$t_{PLL\,CIN}$	-0.109	-0.122	-0.007	-0.021	-0.037	ns
$t_{PLL\,COUT}$	-0.104	-0.117	-0.011	-0.025	-0.042	ns

Table 5–47. EP2S15 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.206	1.262	2.113	2.422	2.815	ns
t_{COUT}	1.211	1.267	2.109	2.418	2.810	ns
t_{PLLCIN}	-0.125	-0.138	-0.023	-0.038	-0.056	ns
$t_{PLLCOUT}$	-0.12	-0.133	-0.027	-0.042	-0.061	ns

EP2S30 Clock Timing Parameters

Tables 5–48 through 5–51 show the maximum clock timing parameters for EP2S30 devices.

Table 5–48. EP2S30 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.553	1.627	2.639	3.025	3.509	ns
t_{COUT}	1.396	1.462	2.397	2.747	3.185	ns
t_{PLLCIN}	0.114	0.113	0.225	0.248	0.28	ns
$t_{PLLCOUT}$	-0.043	-0.052	-0.017	-0.03	-0.044	ns

Table 5–49. EP2S30 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.539	1.613	2.622	3.008	3.501	ns
t_{COUT}	1.382	1.448	2.380	2.730	3.177	ns
t_{PLLCIN}	0.101	0.098	0.209	0.229	0.267	ns
$t_{PLLCOUT}$	-0.056	-0.067	-0.033	-0.049	-0.057	ns

Table 5–50. EP2S30 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.304	1.184	1.966	2.251	2.616	ns
t_{COUT}	1.309	1.189	1.962	2.247	2.611	ns
t_{PLLCIN}	-0.135	-0.158	-0.208	-0.254	-0.302	ns
$t_{PLLCOUT}$	-0.13	-0.153	-0.212	-0.258	-0.307	ns

Table 5–51. EP2S30 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.289	1.352	2.238	2.567	2.990	ns
t_{COUT}	1.294	1.357	2.234	2.563	2.985	ns
t_{PLLCIN}	-0.14	-0.154	-0.169	-0.205	-0.254	ns
$t_{PLLCOUT}$	-0.135	-0.149	-0.173	-0.209	-0.259	ns

EP2S60 Clock Timing Parameters

Tables 5–52 through 5–55 show the maximum clock timing parameters for EP2S60 devices.

Table 5–52. EP2S60 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.681	1.762	2.945	3.381	3.931	ns
t_{COUT}	1.524	1.597	2.703	3.103	3.607	ns
t_{PLLCIN}	0.066	0.064	0.279	0.311	0.348	ns
$t_{PLLCOUT}$	-0.091	-0.101	0.037	0.033	0.024	ns

Table 5–53. EP2S60 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.658	1.739	2.920	3.350	3.899	ns
t_{COUT}	1.501	1.574	2.678	3.072	3.575	ns
$t_{PLL\,CIN}$	0.06	0.057	0.278	0.304	0.355	ns
$t_{PLL\,COUT}$	-0.097	-0.108	0.036	0.026	0.031	ns

Table 5–54. EP2S60 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.463	1.532	2.591	2.972	3.453	ns
t_{COUT}	1.468	1.537	2.587	2.968	3.448	ns
$t_{PLL\,CIN}$	-0.153	-0.167	-0.079	-0.099	-0.128	ns
$t_{PLL\,COUT}$	-0.148	-0.162	-0.083	-0.103	-0.133	ns

Table 5–55. EP2S60 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.439	1.508	2.562	2.940	3.421	ns
t_{COUT}	1.444	1.513	2.558	2.936	3.416	ns
$t_{PLL\,CIN}$	-0.161	-0.174	-0.083	-0.107	-0.126	ns
$t_{PLL\,COUT}$	-0.156	-0.169	-0.087	-0.111	-0.131	ns

EP2S90 Clock Timing Parameters

Tables 5–56 through 5–59 show the maximum clock timing parameters for EP2S90 devices.

Table 5–56. EP2S90 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.768	1.850	3.033	3.473	4.040	ns
t_{COUT}	1.611	1.685	2.791	3.195	3.716	ns
t_{PLLCIN}	-0.127	-0.117	0.125	0.129	0.144	ns
$t_{PLLCOUT}$	-0.284	-0.282	-0.117	-0.149	-0.18	ns

Table 5–57. EP2S90 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.783	1.868	3.058	3.502	4.070	ns
t_{COUT}	1.626	1.703	2.816	3.224	3.746	ns
t_{PLLCIN}	-0.137	-0.127	0.115	0.119	0.134	ns
$t_{PLLCOUT}$	-0.294	-0.292	-0.127	-0.159	-0.19	ns

Table 5–58. EP2S90 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.566	1.638	2.731	3.124	3.632	ns
t_{COUT}	1.571	1.643	2.727	3.120	3.627	ns
t_{PLLCIN}	-0.326	-0.326	-0.178	-0.218	-0.264	ns
$t_{PLLCOUT}$	-0.321	-0.321	-0.182	-0.222	-0.269	ns

Table 5–59. EP2S90 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.585	1.658	2.757	3.154	3.665	ns
t_{COUT}	1.590	1.663	2.753	3.150	3.660	ns
t_{PLLCIN}	-0.341	-0.341	-0.193	-0.235	-0.278	ns
$t_{PLLCOUT}$	-0.336	-0.336	-0.197	-0.239	-0.283	ns

EP2S130 Clock Timing Parameters

Tables 5–60 through 5–63 show the maximum clock timing parameters for EP2S130 devices.

Table 5–60. EP2S130 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.889	1.981	3.405	3.722	4.326	ns
t_{COUT}	1.732	1.816	3.151	3.444	4.002	ns
t_{PLLCIN}	0.105	0.106	0.226	0.242	0.277	ns
$t_{PLLCOUT}$	-0.052	-0.059	-0.028	-0.036	-0.047	ns

Table 5–61. EP2S130 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.907	1.998	3.420	3.740	4.348	ns
t_{COUT}	1.750	1.833	3.166	3.462	4.024	ns
t_{PLLCIN}	0.134	0.136	0.276	0.296	0.338	ns
$t_{PLLCOUT}$	-0.023	-0.029	0.022	0.018	0.014	ns

Table 5–62. EP2S130 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.680	1.760	3.070	3.351	3.892	ns
t_{COUT}	1.685	1.765	3.066	3.347	3.887	ns
t_{PLLCIN}	-0.113	-0.124	-0.12	-0.138	-0.168	ns
$t_{PLLCOUT}$	-0.108	-0.119	-0.124	-0.142	-0.173	ns

Table 5–63. EP2S130 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.690	1.770	3.075	3.362	3.905	ns
t_{COUT}	1.695	1.775	3.071	3.358	3.900	ns
t_{PLLCIN}	-0.087	-0.097	-0.075	-0.089	-0.11	ns
$t_{PLLCOUT}$	-0.082	-0.092	-0.079	-0.093	-0.115	ns

EP2S180 Clock Timing Parameters

Tables 5–64 through 5–67 show the maximum clock timing parameters for EP2S180 devices.

Table 5–64. EP2S180 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	2.001	2.095	3.643	3.984	4.634	ns
t_{COUT}	1.844	1.930	3.389	3.706	4.310	ns
t_{PLLCIN}	-0.307	-0.297	0.053	0.046	0.048	ns
$t_{PLLCOUT}$	-0.464	-0.462	-0.201	-0.232	-0.276	ns

Table 5–65. EP2S180 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	2.003	2.100	3.652	3.993	4.648	ns
t_{COUT}	1.846	1.935	3.398	3.715	4.324	ns
$t_{PLL\,CIN}$	-0.3	-0.29	0.053	0.054	0.058	ns
$t_{PLL\,COUT}$	-0.457	-0.455	-0.201	-0.224	-0.266	ns

Table 5–66. EP2S180 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.759	1.844	3.273	3.577	4.162	ns
t_{COUT}	1.764	1.849	3.269	3.573	4.157	ns
$t_{PLL\,CIN}$	-0.542	-0.541	-0.317	-0.353	-0.414	ns
$t_{PLL\,COUT}$	-0.537	-0.536	-0.321	-0.357	-0.419	ns

Table 5–67. EP2S180 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.763	1.850	3.285	3.588	4.176	ns
t_{COUT}	1.768	1.855	3.281	3.584	4.171	ns
$t_{PLL\,CIN}$	-0.542	-0.542	-0.319	-0.355	-0.42	ns
$t_{PLL\,COUT}$	-0.537	-0.537	-0.323	-0.359	-0.425	ns

Clock Network Skew Adders

The Quartus II software models skew within dedicated clock networks such as global and regional clocks. Therefore, intra-clock network skew adder is not specified. Table 5–68 specifies the clock skew between any two clock networks driving registers in the IOE.

Name	Description	Min	Typ	Max	Unit
Clock skew adder EP2S15, EP2S30, EP2S60 (1)	Inter-clock network, same side			±50	ps
	Inter-clock network, entire chip			±100	ps
Clock skew adder EP2S90 (1)	Inter-clock network, same side			±55	ps
	Inter-clock network, entire chip			±110	ps
Clock skew adder EP2S130 (1)	Inter-clock network, same side			±63	ps
	Inter-clock network, entire chip			±125	ps
Clock skew adder EP2S180 (1)	Inter-clock network, same side			±75	ps
	Inter-clock network, entire chip			±150	ps

Note to Table 5–68:

(1) This is in addition to intra-clock network skew, which is modeled in the Quartus II software.

IOE Programmable Delay

See Tables 5–69 and 5–70 for IOE programmable delay.

Parameter	Paths Affected	Available Settings	Minimum Timing (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade	
			Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)
Input delay from pin to internal cells	Pad to I/O dataout to logic array	8	0 0	1,696 1,781	0 0	2,881 3,025	0	3,313	0	3,860
Input delay from pin to input register	Pad to I/O input register	64	0 0	1,955 2,053	0 0	3,275 3,439	0	3,766	0	4,388
Delay from output register to output pin	I/O output register to pad	2	0 0	316 332	0 0	500 525	0	575	0	670
Output enable pin delay	t_{xz} , t_{zx}	2	0 0	305 320	0 0	483 507	0	556	0	647

Notes to Table 5–69:

- (1) The incremental values for the settings are generally linear. For the exact delay associated with each setting, use the latest version of the Quartus II software.
- (2) The first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.
- (3) The first number applies to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices. The second number applies to -3 speed grade EP2S130 and EP2S180 devices.

Parameter	Paths Affected	Available Settings	Minimum Timing (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade	
			Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)
Input delay from pin to internal cells	Pad to I/O dataout to logic array	8	0 0	1,697 1,782	0 0	2,876 3,020	0	3,308	0	3,853
Input delay from pin to input register	Pad to I/O input register	64	0 0	1,956 2,054	0 0	3,270 3,434	0	3,761	0	4,381
Delay from output register to output pin	I/O output register to pad	2	0 0	316 332	0 0	525 525	0	575	0	670
Output enable pin delay	t_{xz} , t_{zx}	2	0 0	305 320	0 0	507 507	0	556	0	647

Notes to Table 5–70:

- (1) The incremental values for the settings are generally linear. For the exact delay associated with each setting, use the latest version of the Quartus II software.
- (2) The first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.
- (3) The first number applies to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices. The second number applies to -3 speed grade EP2S130 and EP2S180 devices.

Default Capacitive Loading of Different I/O Standards

See [Table 5–71](#) for default capacitive loading of different I/O standards.

I/O Standard	Capacitive Load	Unit
LVTTTL	0	pF
LVC MOS	0	pF
2.5 V	0	pF
1.8 V	0	pF
1.5 V	0	pF
PCI	10	pF
PCI-X	10	pF
SSTL-2 Class I	0	pF

Table 5–71. Default Loading of Different I/O Standards for Stratix II (Part 2 of 2)

I/O Standard	Capacitive Load	Unit
SSTL-2 Class II	0	pF
SSTL-18 Class I	0	pF
SSTL-18 Class II	0	pF
1.5-V HSTL Class I	0	pF
1.5-V HSTL Class II	0	pF
1.8-V HSTL Class I	0	pF
1.8-V HSTL Class II	0	pF
1.2-V HSTL with OCT	0	pF
Differential SSTL-2 Class I	0	pF
Differential SSTL-2 Class II	0	pF
Differential SSTL-18 Class I	0	pF
Differential SSTL-18 Class II	0	pF
1.5-V Differential HSTL Class I	0	pF
1.5-V Differential HSTL Class II	0	pF
1.8-V Differential HSTL Class I	0	pF
1.8-V Differential HSTL Class II	0	pF
LVDS	0	pF
HyperTransport	0	pF
LVPECL	0	pF

I/O Delays

See Tables 5-72 through 5-76 for I/O delays.

Table 5-72. I/O Delay Parameters

Symbol	Parameter
t_{DIP}	Delay from I/O datain to output pad
t_{OP}	Delay from I/O output register to output pad
t_{PCOUT}	Delay from input pad to I/O dataout to core
t_{PI}	Delay from input pad to I/O input register

Table 5-73. Stratix II I/O Input Delay for Column Pins (Part 1 of 3)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial	(2)	(3)			
LVTTTL	t_{PI}	674	707	1223	1282	1405	1637	ps
	t_{PCOUT}	408	428	787	825	904	1054	ps
2.5 V	t_{PI}	684	717	1210	1269	1390	1619	ps
	t_{PCOUT}	418	438	774	812	889	1036	ps
1.8 V	t_{PI}	747	783	1366	1433	1570	1829	ps
	t_{PCOUT}	481	504	930	976	1069	1246	ps
1.5 V	t_{PI}	749	786	1436	1506	1650	1922	ps
	t_{PCOUT}	483	507	1000	1049	1149	1339	ps
LVCMOS	t_{PI}	674	707	1223	1282	1405	1637	ps
	t_{PCOUT}	408	428	787	825	904	1054	ps
SSTL-2 Class I	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
SSTL-2 Class II	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
SSTL-18 Class I	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
SSTL-18 Class II	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.5-V HSTL Class I	t_{PI}	560	587	993	1041	1141	1329	ps
	t_{PCOUT}	294	308	557	584	640	746	ps

Table 5–73. Stratix II I/O Input Delay for Column Pins (Part 2 of 3)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial					
1.5-V HSTL Class II	t_{PI}	560	587	993	1041	1141	1329	ps
	t_{PCOUT}	294	308	557	584	640	746	ps
1.8-V HSTL Class I	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.8-V HSTL Class II	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
PCI	t_{PI}	679	712	1214	1273	1395	1625	ps
	t_{PCOUT}	413	433	778	816	894	1042	ps
PCI-X	t_{PI}	679	712	1214	1273	1395	1625	ps
	t_{PCOUT}	413	433	778	816	894	1042	ps
Differential SSTL-2 Class I (1)	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
Differential SSTL-2 Class II (1)	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
Differential SSTL-18 Class I (1)	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
Differential SSTL-18 Class II (1)	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.8-V Differential HSTL Class I (1)	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.8-V Differential HSTL Class II (1)	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.5-V Differential HSTL Class I (1)	t_{PI}	560	587	993	1041	1141	1329	ps
	t_{PCOUT}	294	308	557	584	640	746	ps
1.5-V Differential HSTL Class II (1)	t_{PI}	560	587	993	1041	1141	1329	ps
	t_{PCOUT}	294	308	557	584	640	746	ps

Table 5–73. Stratix II I/O Input Delay for Column Pins (Part 3 of 3)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial	(2)	(3)			
1.2-V HSTL	t_{PI}	645	677	1194	1252	-	-	ps
	t_{PCOUT}	379	398	758	795	-	-	ps

Notes for Table 5–73:

- (1) These I/O standards are only supported on DQS pins.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.

Table 5–74. Stratix II I/O Input Delay for Row Pins (Part 1 of 2)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial	(1)	(2)			
LVTTTL	t_{PI}	715	749	1287	1350	1477	1723	ps
	t_{PCOUT}	391	410	760	798	873	1018	ps
2.5 V	t_{PI}	726	761	1273	1335	1461	1704	ps
	t_{PCOUT}	402	422	746	783	857	999	ps
1.8 V	t_{PI}	788	827	1427	1497	1639	1911	ps
	t_{PCOUT}	464	488	900	945	1035	1206	ps
1.5 V	t_{PI}	792	830	1498	1571	1720	2006	ps
	t_{PCOUT}	468	491	971	1019	1116	1301	ps
LVCMOS	t_{PI}	715	749	1287	1350	1477	1723	ps
	t_{PCOUT}	391	410	760	798	873	1018	ps
SSTL-2 Class I	t_{PI}	547	573	879	921	1008	1176	ps
	t_{PCOUT}	223	234	352	369	404	471	ps
SSTL-2 Class II	t_{PI}	547	573	879	921	1008	1176	ps
	t_{PCOUT}	223	234	352	369	404	471	ps
SSTL-18 Class I	t_{PI}	577	605	960	1006	1101	1285	ps
	t_{PCOUT}	253	266	433	454	497	580	ps
SSTL-18 Class II	t_{PI}	577	605	960	1006	1101	1285	ps
	t_{PCOUT}	253	266	433	454	497	580	ps
1.5-V HSTL Class I	t_{PI}	602	631	1056	1107	1212	1413	ps
	t_{PCOUT}	278	292	529	555	608	708	ps

Table 5–74. Stratix II I/O Input Delay for Row Pins (Part 2 of 2)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial	(1)	(2)			
1.5-V HSTL Class II	t_{PI}	602	631	1056	1107	1212	1413	ps
	t_{PCOUT}	278	292	529	555	608	708	ps
1.8-V HSTL Class I	t_{PI}	577	605	960	1006	1101	1285	ps
	t_{PCOUT}	253	266	433	454	497	580	ps
1.8-V HSTL Class II	t_{PI}	577	605	960	1006	1101	1285	ps
	t_{PCOUT}	253	266	433	454	497	580	ps
LVDS	t_{PI}	515	540	948	994	1088	1269	ps
	t_{PCOUT}	191	201	421	442	484	564	ps
HyperTransport	t_{PI}	515	540	948	994	1088	1269	ps
	t_{PCOUT}	191	201	421	442	484	564	ps

Notes for Table 5–74:

- (1) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
(2) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 1 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
			Industrial	Commercial	(3)	(4)			
LVTTTL	4 mA	t_{OP}	1178	1236	2351	2467	2702	2820	ps
		t_{DIP}	1198	1258	2417	2537	2778	2910	ps
	8 mA	t_{OP}	1041	1091	2036	2136	2340	2448	ps
		t_{DIP}	1061	1113	2102	2206	2416	2538	ps
	12 mA	t_{OP}	976	1024	2036	2136	2340	2448	ps
		t_{DIP}	996	1046	2102	2206	2416	2538	ps
	16 mA	t_{OP}	951	998	1893	1986	2176	2279	ps
		t_{DIP}	971	1020	1959	2056	2252	2369	ps
	20 mA	t_{OP}	931	976	1787	1875	2054	2154	ps
		t_{DIP}	951	998	1853	1945	2130	2244	ps
	24 mA (1)	t_{OP}	924	969	1788	1876	2055	2156	ps
		t_{DIP}	944	991	1854	1946	2131	2246	ps

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 2 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
LVCMOS	4 mA	t_{OP}	1041	1091	2036	2136	2340	2448	ps	
		t_{DIP}	1061	1113	2102	2206	2416	2538	ps	
	8 mA	t_{OP}	952	999	1786	1874	2053	2153	ps	
		t_{DIP}	972	1021	1852	1944	2129	2243	ps	
	12 mA	t_{OP}	926	971	1720	1805	1977	2075	ps	
		t_{DIP}	946	993	1786	1875	2053	2165	ps	
	16 mA	t_{OP}	933	978	1693	1776	1946	2043	ps	
		t_{DIP}	953	1000	1759	1846	2022	2133	ps	
	20 mA	t_{OP}	921	965	1677	1759	1927	2025	ps	
		t_{DIP}	941	987	1743	1829	2003	2115	ps	
	24 mA (1)	t_{OP}	909	954	1659	1741	1906	2003	ps	
		t_{DIP}	929	976	1725	1811	1982	2093	ps	
	2.5 V	4 mA	t_{OP}	1004	1053	2063	2165	2371	2480	ps
			t_{DIP}	1024	1075	2129	2235	2447	2570	ps
8 mA		t_{OP}	955	1001	1841	1932	2116	2218	ps	
		t_{DIP}	975	1023	1907	2002	2192	2308	ps	
12 mA		t_{OP}	934	980	1742	1828	2002	2101	ps	
		t_{DIP}	954	1002	1808	1898	2078	2191	ps	
16 mA (1)		t_{OP}	918	962	1679	1762	1929	2027	ps	
		t_{DIP}	938	984	1745	1832	2005	2117	ps	

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 3 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
1.8 V	2 mA	t _{OP}	1042	1093	2904	3048	3338	3472	ps	
		t _{DIP}	1062	1115	2970	3118	3414	3562	ps	
	4 mA	t _{OP}	1047	1098	2248	2359	2584	2698	ps	
		t _{DIP}	1067	1120	2314	2429	2660	2788	ps	
	6 mA	t _{OP}	974	1022	2024	2124	2326	2434	ps	
		t _{DIP}	994	1044	2090	2194	2402	2524	ps	
	8 mA	t _{OP}	976	1024	1947	2043	2238	2343	ps	
		t _{DIP}	996	1046	2013	2113	2314	2433	ps	
	10 mA	t _{OP}	933	978	1882	1975	2163	2266	ps	
		t _{DIP}	953	1000	1948	2045	2239	2356	ps	
	12 mA (1)	t _{OP}	934	979	1833	1923	2107	2209	ps	
		t _{DIP}	954	1001	1899	1993	2183	2299	ps	
	1.5 V	2 mA	t _{OP}	1023	1073	2505	2629	2879	3002	ps
			t _{DIP}	1043	1095	2571	2699	2955	3092	ps
4 mA		t _{OP}	963	1009	2023	2123	2325	2433	ps	
		t _{DIP}	983	1031	2089	2193	2401	2523	ps	
6 mA		t _{OP}	966	1012	1923	2018	2210	2315	ps	
		t _{DIP}	986	1034	1989	2088	2286	2405	ps	
8 mA (1)		t _{OP}	926	971	1878	1970	2158	2262	ps	
		t _{DIP}	946	993	1944	2040	2234	2352	ps	
SSTL-2 Class I		8 mA	t _{OP}	913	957	1715	1799	1971	2041	ps
			t _{DIP}	933	979	1781	1869	2047	2131	ps
	12 mA (1)	t _{OP}	896	940	1672	1754	1921	1991	ps	
		t _{DIP}	916	962	1738	1824	1997	2081	ps	
SSTL-2 Class II	16 mA	t _{OP}	876	918	1609	1688	1849	1918	ps	
		t _{DIP}	896	940	1675	1758	1925	2008	ps	
	20 mA	t _{OP}	877	919	1598	1676	1836	1905	ps	
		t _{DIP}	897	941	1664	1746	1912	1995	ps	
	24 mA (1)	t _{OP}	872	915	1596	1674	1834	1903	ps	
		t _{DIP}	892	937	1662	1744	1910	1993	ps	

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 4 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
SSTL-18 Class I	4 mA	t _{OP}	909	953	1690	1773	1942	2012	ps	
		t _{DIP}	929	975	1756	1843	2018	2102	ps	
	6 mA	t _{OP}	914	958	1656	1737	1903	1973	ps	
		t _{DIP}	934	980	1722	1807	1979	2063	ps	
	8 mA	t _{OP}	894	937	1640	1721	1885	1954	ps	
		t _{DIP}	914	959	1706	1791	1961	2044	ps	
	10 mA	t _{OP}	898	942	1638	1718	1882	1952	ps	
		t _{DIP}	918	964	1704	1788	1958	2042	ps	
	12 mA (1)	t _{OP}	891	936	1626	1706	1869	1938	ps	
		t _{DIP}	911	958	1692	1776	1945	2028	ps	
	SSTL-18 Class II	8 mA	t _{OP}	883	925	1597	1675	1835	1904	ps
			t _{DIP}	903	947	1663	1745	1911	1994	ps
16 mA		t _{OP}	894	937	1578	1655	1813	1882	ps	
		t _{DIP}	914	959	1644	1725	1889	1972	ps	
18 mA		t _{OP}	890	933	1585	1663	1821	1890	ps	
		t _{DIP}	910	955	1651	1733	1897	1980	ps	
20 mA (1)		t _{OP}	890	933	1583	1661	1819	1888	ps	
		t _{DIP}	910	955	1649	1731	1895	1978	ps	
1.8-V HSTL Class I		4 mA	t _{OP}	912	956	1608	1687	1848	1943	ps
			t _{DIP}	932	978	1674	1757	1924	2033	ps
	6 mA	t _{OP}	917	962	1595	1673	1833	1928	ps	
		t _{DIP}	937	984	1661	1743	1909	2018	ps	
	8 mA	t _{OP}	896	940	1586	1664	1823	1917	ps	
		t _{DIP}	916	962	1652	1734	1899	2007	ps	
	10 mA	t _{OP}	900	944	1591	1669	1828	1923	ps	
		t _{DIP}	920	966	1657	1739	1904	2013	ps	
	12 mA (1)	t _{OP}	892	936	1585	1663	1821	1916	ps	
		t _{DIP}	912	958	1651	1733	1897	2006	ps	

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 5 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
1.8-V HSTL Class II	16 mA	t_{OP}	877	919	1385	1453	1591	1680	ps	
		t_{DIP}	897	941	1451	1523	1667	1770	ps	
	18 mA	t_{OP}	879	921	1394	1462	1602	1691	ps	
		t_{DIP}	899	943	1460	1532	1678	1781	ps	
	20 mA (1)	t_{OP}	879	921	1402	1471	1611	1700	ps	
		t_{DIP}	899	943	1468	1541	1687	1790	ps	
1.5-V HSTL Class I	4 mA	t_{OP}	912	956	1607	1686	1847	1942	ps	
		t_{DIP}	932	978	1673	1756	1923	2032	ps	
	6 mA	t_{OP}	917	961	1588	1666	1825	1920	ps	
		t_{DIP}	937	983	1654	1736	1901	2010	ps	
	8 mA	t_{OP}	899	943	1590	1668	1827	1922	ps	
		t_{DIP}	919	965	1656	1738	1903	2012	ps	
	10 mA	t_{OP}	900	943	1592	1670	1829	1924	ps	
		t_{DIP}	920	965	1658	1740	1905	2014	ps	
	12 mA (1)	t_{OP}	893	937	1590	1668	1827	1922	ps	
		t_{DIP}	913	959	1656	1738	1903	2012	ps	
	1.5-V HSTL Class II	16 mA	t_{OP}	881	924	1431	1501	1644	1734	ps
			t_{DIP}	901	946	1497	1571	1720	1824	ps
18 mA		t_{OP}	884	927	1439	1510	1654	1744	ps	
		t_{DIP}	904	949	1505	1580	1730	1834	ps	
20 mA (1)		t_{OP}	886	929	1450	1521	1666	1757	ps	
		t_{DIP}	906	951	1516	1591	1742	1847	ps	
1.2-V HSTL		t_{OP}	958	1004	1602	1681	-	-	ps	
		t_{DIP}	978	1026	1668	1751	-	-	ps	
PCI		t_{OP}	1028	1082	1956	2051	2244	2070	ps	
		t_{DIP}	1048	1104	2022	2121	2320	2160	ps	
PCI-X		t_{OP}	1028	1082	1956	2051	2244	2070	ps	
		t_{DIP}	1048	1104	2022	2121	2320	2160	ps	

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 6 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
Differential SSTL-2 Class I	8 mA	t_{OP}	913	957	1715	1799	1971	2041	ps	
		t_{DIP}	933	979	1781	1869	2047	2131	ps	
	12 mA	t_{OP}	896	940	1672	1754	1921	1991	ps	
		t_{DIP}	916	962	1738	1824	1997	2081	ps	
Differential SSTL-2 Class II	16 mA	t_{OP}	876	918	1609	1688	1849	1918	ps	
		t_{DIP}	896	940	1675	1758	1925	2008	ps	
	20 mA	t_{OP}	877	919	1598	1676	1836	1905	ps	
		t_{DIP}	897	941	1664	1746	1912	1995	ps	
	24 mA	t_{OP}	872	915	1596	1674	1834	1903	ps	
		t_{DIP}	892	937	1662	1744	1910	1993	ps	
Differential SSTL-18 Class I	4 mA	t_{OP}	909	953	1690	1773	1942	2012	ps	
		t_{DIP}	929	975	1756	1843	2018	2102	ps	
	6 mA	t_{OP}	914	958	1656	1737	1903	1973	ps	
		t_{DIP}	934	980	1722	1807	1979	2063	ps	
	8 mA	t_{OP}	894	937	1640	1721	1885	1954	ps	
		t_{DIP}	914	959	1706	1791	1961	2044	ps	
	10 mA	t_{OP}	898	942	1638	1718	1882	1952	ps	
		t_{DIP}	918	964	1704	1788	1958	2042	ps	
	12 mA	t_{OP}	891	936	1626	1706	1869	1938	ps	
		t_{DIP}	911	958	1692	1776	1945	2028	ps	
	Differential SSTL-18 Class II	8 mA	t_{OP}	883	925	1597	1675	1835	1904	ps
			t_{DIP}	903	947	1663	1745	1911	1994	ps
16 mA		t_{OP}	894	937	1578	1655	1813	1882	ps	
		t_{DIP}	914	959	1644	1725	1889	1972	ps	
18 mA		t_{OP}	890	933	1585	1663	1821	1890	ps	
		t_{DIP}	910	955	1651	1733	1897	1980	ps	
20 mA		t_{OP}	890	933	1583	1661	1819	1888	ps	
		t_{DIP}	910	955	1649	1731	1895	1978	ps	

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 7 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
1.8-V Differential HSTL Class I	4 mA	t _{OP}	912	956	1608	1687	1848	1943	ps	
		t _{DIP}	932	978	1674	1757	1924	2033	ps	
	6 mA	t _{OP}	917	962	1595	1673	1833	1928	ps	
		t _{DIP}	937	984	1661	1743	1909	2018	ps	
	8 mA	t _{OP}	896	940	1586	1664	1823	1917	ps	
		t _{DIP}	916	962	1652	1734	1899	2007	ps	
	10 mA	t _{OP}	900	944	1591	1669	1828	1923	ps	
		t _{DIP}	920	966	1657	1739	1904	2013	ps	
	12 mA	t _{OP}	892	936	1585	1663	1821	1916	ps	
		t _{DIP}	912	958	1651	1733	1897	2006	ps	
	1.8-V Differential HSTL Class II	16 mA	t _{OP}	877	919	1385	1453	1591	1680	ps
			t _{DIP}	897	941	1451	1523	1667	1770	ps
18 mA		t _{OP}	879	921	1394	1462	1602	1691	ps	
		t _{DIP}	899	943	1460	1532	1678	1781	ps	
20 mA		t _{OP}	879	921	1402	1471	1611	1700	ps	
		t _{DIP}	899	943	1468	1541	1687	1790	ps	
1.5-V Differential HSTL Class I	4 mA	t _{OP}	912	956	1607	1686	1847	1942	ps	
		t _{DIP}	932	978	1673	1756	1923	2032	ps	
	6 mA	t _{OP}	917	961	1588	1666	1825	1920	ps	
		t _{DIP}	937	983	1654	1736	1901	2010	ps	
	8 mA	t _{OP}	899	943	1590	1668	1827	1922	ps	
		t _{DIP}	919	965	1656	1738	1903	2012	ps	
	10 mA	t _{OP}	900	943	1592	1670	1829	1924	ps	
		t _{DIP}	920	965	1658	1740	1905	2014	ps	
	12 mA	t _{OP}	893	937	1590	1668	1827	1922		
		t _{DIP}	913	959	1656	1738	1903	2012		

Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 8 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
			Industrial	Commercial	(3)	(4)			
1.5-V Differential HSTL Class II	16 mA	t _{OP}	881	924	1431	1501	1644	1734	ps
		t _{DIP}	901	946	1497	1571	1720	1824	ps
	18 mA	t _{OP}	884	927	1439	1510	1654	1744	
		t _{DIP}	904	949	1505	1580	1730	1834	
	20 mA	t _{OP}	886	929	1450	1521	1666	1757	
		t _{DIP}	906	951	1516	1591	1742	1847	

Notes to Table 5–75:

- (1) This is the default setting in the Quartus II software.
- (2) These I/O standards are only supported on DQS pins.
- (3) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (4) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.

Table 5–76. Stratix II I/O Output Delay for Row Pins (Part 1 of 3)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade	-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
			Industrial	Commercial	(2)	(3)			
LVTTTL	4 mA	t _{OP}	1267	1328	2655	2786	3052	3189	ps
		t _{DIP}	1225	1285	2600	2729	2989	3116	ps
	8 mA	t _{OP}	1144	1200	2113	2217	2429	2549	ps
		t _{DIP}	1102	1157	2058	2160	2366	2476	ps
	12 mA (1)	t _{OP}	1091	1144	2081	2184	2392	2512	ps
		t _{DIP}	1049	1101	2026	2127	2329	2439	ps
LVCMOS	4 mA	t _{OP}	1144	1200	2113	2217	2429	2549	ps
		t _{DIP}	1102	1157	2058	2160	2366	2476	ps
	8 mA (1)	t _{OP}	1044	1094	1853	1944	2130	2243	ps
		t _{DIP}	1002	1051	1798	1887	2067	2170	ps

Table 5–76. Stratix II I/O Output Delay for Row Pins (Part 2 of 3)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
2.5 V	4 mA	t _{OP}	1128	1183	2091	2194	2403	2523	ps	
		t _{DIP}	1086	1140	2036	2137	2340	2450	ps	
	8 mA	t _{OP}	1030	1080	1872	1964	2152	2265	ps	
		t _{DIP}	988	1037	1817	1907	2089	2192	ps	
	12 mA (1)	t _{OP}	1012	1061	1775	1862	2040	2151	ps	
		t _{DIP}	970	1018	1720	1805	1977	2078	ps	
1.8 V	2 mA	t _{OP}	1196	1253	2954	3100	3396	3542	ps	
		t _{DIP}	1154	1210	2899	3043	3333	3469	ps	
	4 mA	t _{OP}	1184	1242	2294	2407	2637	2763	ps	
		t _{DIP}	1142	1199	2239	2350	2574	2690	ps	
	6 mA	t _{OP}	1079	1131	2039	2140	2344	2462	ps	
		t _{DIP}	1037	1088	1984	2083	2281	2389	ps	
	8 mA (1)	t _{OP}	1049	1100	1942	2038	2232	2348	ps	
		t _{DIP}	1007	1057	1887	1981	2169	2275	ps	
	1.5 V	2 mA	t _{OP}	1158	1213	2530	2655	2908	3041	ps
			t _{DIP}	1116	1170	2475	2598	2845	2968	ps
4 mA		t _{OP}	1055	1106	2020	2120	2322	2440	ps	
		t _{DIP}	1013	1063	1965	2063	2259	2367	ps	
SSTL-2 Class I	8 mA	t _{OP}	1002	1050	1759	1846	2022	2104	ps	
		t _{DIP}	960	1007	1704	1789	1959	2031	ps	
SSTL-2 Class II	16 mA (1)	t _{OP}	947	992	1581	1659	1817	1897	ps	
		t _{DIP}	905	949	1526	1602	1754	1824	ps	
SSTL-18 Class I	4 mA	t _{OP}	990	1038	1709	1793	1964	2046	ps	
		t _{DIP}	948	995	1654	1736	1901	1973	ps	
	6 mA	t _{OP}	994	1042	1648	1729	1894	1975	ps	
		t _{DIP}	952	999	1593	1672	1831	1902	ps	
	8 mA	t _{OP}	970	1018	1633	1713	1877	1958	ps	
		t _{DIP}	928	975	1578	1656	1814	1885	ps	
	10 mA (1)	t _{OP}	974	1021	1615	1694	1856	1937	ps	
		t _{DIP}	932	978	1560	1637	1793	1864	ps	

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit	
			Industrial	Commercial						
1.8-V HSTL Class I	4 mA	t _{OP}	972	1019	1610	1689	1850	1956	ps	
		t _{DIP}	930	976	1555	1632	1787	1883	ps	
	6 mA	t _{OP}	975	1022	1580	1658	1816	1920	ps	
		t _{DIP}	933	979	1525	1601	1753	1847	ps	
	8 mA	t _{OP}	958	1004	1576	1653	1811	1916	ps	
		t _{DIP}	916	961	1521	1596	1748	1843	ps	
	10 mA	t _{OP}	962	1008	1567	1644	1801	1905	ps	
		t _{DIP}	920	965	1512	1587	1738	1832	ps	
	12 mA (1)	t _{OP}	953	999	1566	1643	1800	1904	ps	
		t _{DIP}	911	956	1511	1586	1737	1831	ps	
	1.5-V HSTL Class I	4 mA	t _{OP}	970	1018	1591	1669	1828	1933	ps
			t _{DIP}	928	975	1536	1612	1765	1860	ps
6 mA		t _{OP}	974	1021	1579	1657	1815	1919	ps	
		t _{DIP}	932	978	1524	1600	1752	1846	ps	
8 mA (1)		t _{OP}	960	1006	1572	1649	1807	1911	ps	
		t _{DIP}	918	963	1517	1592	1744	1838	ps	
LVDS		t _{OP}	1018	1067	1723	1808	1980	2089	ps	
		t _{DIP}	976	1024	1668	1751	1917	2016	ps	
HyperTransport		t _{OP}	1005	1053	1723	1808	1980	2089	ps	
		t _{DIP}	963	1010	1668	1751	1917	2016	ps	

Notes to Table 5–76:

- (1) This is the default setting in the Quartus II software.
- (2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
- (3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.

Maximum Input & Output Clock Toggle Rate

Maximum clock toggle rate is defined as the maximum frequency achievable for a clock type signal at an I/O pin. The I/O pin can be a regular I/O pin or a dedicated clock I/O pin.

The maximum clock toggle rate is different from the maximum data bit rate. If the maximum clock toggle rate on a regular I/O pin is 300 MHz, the maximum data bit rate for dual data rate (DDR) could be potentially as high as 600 Mbps on the same I/O pin.

Table 5–77 specifies the maximum input clock toggle rates. Table 5–78 specifies the maximum output clock toggle rates at 0pF load. Table 5–79 specifies the derating factors for the output clock toggle rate for a non 0pF load.

To calculate the output toggle rate for a non 0pF load, use this formula:

The toggle rate for a non 0pF load

$$= 1000 / (1000 / \text{toggle rate at } 0\text{pF load} + \text{derating factor} * \text{load value in pF} / 1000)$$

For example, the output toggle rate at 0pF load for SSTL-18 Class II 20mA I/O standard is 550 MHz on a -3 device clock output pin. The derating factor is 94ps/pF. For a 10pF load the toggle rate is calculated as:

$$1000 / (1000/550 + 94 \times 10 / 1000) = 363 \text{ (MHz)}$$

Tables 5–77 through 5–79 show the I/O toggle rates for Stratix II devices.

Input I/O Standard	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Dedicated Clock Inputs (MHz)		
	-3	-4	-5	-3	-4	-5	-3	-4	-5
LVTTTL	500	500	450	500	500	450	500	500	400
2.5-V LVTTTL/CMOS	500	500	450	500	500	450	500	500	400
1.8-V LVTTTL/CMOS	500	500	450	500	500	450	500	500	400
1.5-V LVTTTL/CMOS	500	500	450	500	500	450	500	500	400
LVC MOS	500	500	450	500	500	450	500	500	400
SSTL-2 Class I	500	500	500	500	500	500	500	500	500
SSTL-2 Class II	500	500	500	500	500	500	500	500	500
SSTL-18 Class I	500	500	500	500	500	500	500	500	500
SSTL-18 Class II	500	500	500	500	500	500	500	500	500
1.5-V HSTL Class I	500	500	500	500	500	500	500	500	500
1.5-V HSTL Class II	500	500	500	500	500	500	500	500	500
1.8-V HSTL Class I	500	500	500	500	500	500	500	500	500

Table 5–77. Maximum Input Toggle Rate on Stratix II Devices (Part 2 of 2)

Input I/O Standard	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Dedicated Clock Inputs (MHz)		
	-3	-4	-5	-3	-4	-5	-3	-4	-5
1.8-V HSTL Class II	500	500	500	500	500	500	500	500	500
PCI (1)	500	500	450	-	-	-	500	500	400
PCI-X (1)	500	500	450	-	-	-	500	500	400
1.2-V HSTL (2)	280	-	-	-	-	-	280	-	-
Differential SSTL-2 Class I (1), (3)	500	500	500	-	-	-	500	500	500
Differential SSTL-2 Class II (1), (3)	500	500	500	-	-	-	500	500	500
Differential SSTL-18 Class I (1), (3)	500	500	500	-	-	-	500	500	500
Differential SSTL-18 Class II (1), (3)	500	500	500	-	-	-	500	500	500
1.8-V Differential HSTL Class I (1), (3)	500	500	500	-	-	-	500	500	500
1.8-V Differential HSTL Class II (1), (3)	500	500	500	-	-	-	500	500	500
1.5-V Differential HSTL Class I (1), (3)	500	500	500	-	-	-	500	500	500
1.5-V Differential HSTL Class II (1), (3)	500	500	500	-	-	-	500	500	500
HyperTransport technology (4)	-	-	-	520	520	420	717	717	640
LVPECL (1)	-	-	-	-	-	-	450	450	400
LVDS (5)	-	-	-	520	520	420	717	717	640
LVDS (6)	-	-	-	-	-	-	450	450	400

Notes to Table 5–77:

- (1) Row clock inputs don't support PCI, PCI-X, LVPECL, and differential HSTL and SSTL standards.
- (2) 1.2-V HSTL is only supported on column I/O pins.
- (3) Differential HSTL and SSTL standards are only supported on column clock and DQS inputs.
- (4) HyperTransport technology is only supported on row I/O and row dedicated clock input pins.
- (5) These numbers apply to I/O pins and dedicated clock pins in the left and right I/O banks.
- (6) These numbers apply to dedicated clock pins in the top and bottom I/O banks.

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 1 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
3.3-V LVTTTL	4 mA	270	225	210	270	225	210	270	225	210
	8 mA	435	355	325	435	355	325	435	355	325
	12 mA	580	475	420	580	475	420	580	475	420
	16 mA	720	594	520	-	-	-	720	594	520
	20 mA	875	700	610	-	-	-	875	700	610
	24 mA	1,030	794	670	-	-	-	1,030	794	670
3.3-V LVCMOS	4 mA	290	250	230	290	250	230	290	250	230
	8 mA	565	480	440	565	480	440	565	480	440
	12 mA	790	710	670	-	-	-	790	710	670
	16 mA	1,020	925	875	-	-	-	1,020	925	875
	20 mA	1,066	985	935	-	-	-	1,066	985	935
	24 mA	1,100	1,040	1,000	-	-	-	1,100	1,040	1,000
2.5-V LVTTTL/LVCMOS	4 mA	230	194	180	230	194	180	230	194	180
	8 mA	430	380	380	430	380	380	430	380	380
	12 mA	630	575	550	630	575	550	630	575	550
	16 mA	930	845	820	-	-	-	930	845	820
1.8-V LVTTTL/LVCMOS	2 mA	120	109	104	120	109	104	120	109	104
	4 mA	285	250	230	285	250	230	285	250	230
	6 mA	450	390	360	450	390	360	450	390	360
	8 mA	660	570	520	660	570	520	660	570	520
	10 mA	905	805	755	-	-	-	905	805	755
	12 mA	1,131	1,040	990	-	-	-	1,131	1,040	990
1.5-V LVTTTL/LVCMOS	2 mA	244	200	180	244	200	180	244	200	180
	4 mA	470	370	325	470	370	325	470	370	325
	6 mA	550	430	375	-	-	-	550	430	375
	8 mA	625	495	420	-	-	-	625	495	420
SSTL-2 Class I	8 mA	400	300	300	-	-	-	400	300	300
	12 mA	400	400	350	400	350	350	400	400	350
SSTL-2 Class II	16 mA	350	350	300	350	350	300	350	350	300
	20 mA	400	350	350	-	-	-	400	350	350
	24 mA	400	400	350	-	-	-	400	400	350

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
SSTL-18 Class I	4 mA	200	150	150	200	150	150	200	150	150
	6 mA	350	250	200	350	250	200	350	250	200
	8 mA	450	300	300	450	300	300	450	300	300
	10 mA	500	400	400	500	400	400	500	400	400
	12 mA	700	550	400	-	-	-	650	550	400
SSTL-18 Class II	8 mA	200	200	150	-	-	-	200	200	150
	16 mA	400	350	350	-	-	-	400	350	350
	18 mA	450	400	400	-	-	-	450	400	400
	20 mA	550	500	450	-	-	-	550	500	450
1.8-V HSTL Class I	4 mA	300	300	300	300	300	300	300	300	300
	6 mA	500	450	450	500	450	450	500	450	450
	8 mA	650	600	600	650	600	600	650	600	600
	10 mA	700	650	600	700	650	600	700	650	600
	12 mA	700	700	650	700	700	650	700	700	650
1.8-V HSTL Class II	16 mA	500	500	450	-	-	-	500	500	450
	18 mA	550	500	500	-	-	-	550	500	500
	20 mA	650	550	550	-	-	-	550	550	550
1.5-V HSTL Class I	4 mA	350	300	300	350	300	300	350	300	300
	6 mA	500	500	450	500	500	450	500	500	450
	8 mA	700	650	600	700	650	600	700	650	600
	10 mA	700	700	650	-	-	-	700	700	650
	12 mA	700	700	700	-	-	-	700	700	700
1.5-V HSTL Class II	16 mA	600	600	550	-	-	-	600	600	550
	18 mA	650	600	600	-	-	-	650	600	600
	20 mA	700	650	600	-	-	-	700	650	600
Differential SSTL-2 Class I (3)	8 mA	400	300	300	400	300	300	400	300	300
	12 mA	400	400	350	400	400	350	400	400	350
Differential SSTL-2 Class II (3)	16 mA	350	350	300	350	350	300	350	350	300
	20 mA	400	350	350	350	350	297	400	350	350
	24 mA	400	400	350	-	-	-	400	400	350

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 3 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
Differential SSTL-18 Class I (3)	4 mA	200	150	150	200	150	150	200	150	150
	6 mA	350	250	200	350	250	200	350	250	200
	8 mA	450	300	300	450	300	300	450	300	300
	10 mA	500	400	400	500	400	400	500	400	400
	12 mA	700	550	400	350	350	297	650	550	400
Differential SSTL-18 Class II (3)	8 mA	200	200	150	-	-	-	200	200	150
	16 mA	400	350	350	-	-	-	400	350	350
	18 mA	450	400	400	-	-	-	450	400	400
	20 mA	550	500	450	-	-	-	550	500	450
1.8-V Differential HSTL Class I (3)	4 mA	300	300	300	-	-	-	300	300	300
	6 mA	500	450	450	-	-	-	500	450	450
	8 mA	650	600	600	-	-	-	650	600	600
	10 mA	700	650	600	-	-	-	700	650	600
	12 mA	700	700	650	-	-	-	700	700	650
1.8-V Differential HSTL Class II (3)	16 mA	500	500	450	-	-	-	500	500	450
	18 mA	550	500	500	-	-	-	550	500	500
	20 mA	650	550	550	-	-	-	550	550	550
1.5-V Differential HSTL Class I (3)	4 mA	350	300	300	-	-	-	350	300	300
	6 mA	500	500	450	-	-	-	500	500	450
	8 mA	700	650	600	-	-	-	700	650	600
	10 mA	700	700	650	-	-	-	700	700	650
	12 mA	700	700	700	-	-	-	700	700	700
1.5-V Differential HSTL Class II (3)	16 mA	600	600	550	-	-	-	600	600	550
	18 mA	650	600	600	-	-	-	650	600	600
	20 mA	700	650	600	-	-	-	700	650	600
3.3-V PCI		1,000	790	670	-	-	-	1,000	790	670
3.3-V PCI-X		1,000	790	670	-	-	-	1,000	790	670
LVDS (6)		-	-	-	500	500	500	450	400	300
HyperTransport technology (4), (6)					500	500	500	-	-	-
LVPECL (5)		-	-	-	-	-	-	450	400	300
3.3-V LVTTTL	OCT 50 Ω	400	400	350	400	400	350	400	400	350
2.5-V LVTTTL	OCT 50 Ω	350	350	300	350	350	300	350	350	300

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 4 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
1.8-V LVTTTL	OCT 50 Ω	700	550	450	700	550	450	700	550	450
3.3-V LVCMOS	OCT 50 Ω	350	350	300	350	350	300	350	350	300
1.5-V LVCMOS	OCT 50 Ω	550	450	400	550	450	400	550	450	400
SSTL-2 Class I	OCT 50 Ω	600	500	500	600	500	500	600	500	500
SSTL-2 Class II	OCT 25 Ω	600	550	500	600	550	500	600	550	500
SSTL-18 Class I	OCT 50 Ω	560	400	350	590	400	350	450	400	350
SSTL-18 Class II	OCT 25 Ω	550	500	450	-	-	-	550	500	450
1.2-V HSTL (2)	OCT 50 Ω	280	-	-	-	-	-	280	-	-
1.5-V HSTL Class I	OCT 50 Ω	600	550	500	600	550	500	600	550	500
1.8-V HSTL Class I	OCT 50 Ω	650	600	600	650	600	600	650	600	600
1.8-V HSTL Class II	OCT 25 Ω	500	500	450	-	-	-	500	500	450
Differential SSTL-2 Class I	OCT 50 Ω	600	500	500	600	500	500	600	500	500
Differential SSTL-2 Class II	OCT 25 Ω	600	550	500	600	550	500	600	550	500
Differential SSTL-18 Class I	OCT 50 Ω	560	400	350	590	400	350	560	400	350
Differential SSTL-18 Class II	OCT 25 Ω	550	500	450	-	-	-	550	500	450
1.8-V Differential HSTL Class I	OCT 50 Ω	650	600	600	650	600	600	650	600	600
1.8-V Differential HSTL Class II	OCT 25 Ω	500	500	450	-	-	-	500	500	450
1.5-V Differential HSTL Class I	OCT 50 Ω	600	550	500	600	550	500	600	550	500

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 5 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
1.2-V Differential HSTL	OCT 50 Ω	280	-	-	-	-	-	280	-	-

Notes to Table 5–78:

- (1) The toggle rate applies to 0-pF output load for all I/O standards except for LVDS and HyperTransport technology on row I/O pins. For LVDS and HyperTransport technology on row I/O pins, the toggle rates apply to load from 0 to 5pF.
- (2) 1.2-V HSTL is only supported on column I/O pins in I/O banks 4, 7, and 8.
- (3) Differential HSTL and SSTL is only supported on column clock and DQS outputs.
- (4) HyperTransport technology is only supported on row I/O and row dedicated clock input pins.
- (5) LVPECL is only supported on column clock pins.
- (6) Refer to Tables 5–81 through 5–91 if using SERDES block. Use the toggle rate values from the clock output column for PLL output.

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 1 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
3.3-V LVTTTL	4 mA	478	510	510	478	510	510	466	510	510
	8 mA	260	333	333	260	333	333	291	333	333
	12 mA	213	247	247	213	247	247	211	247	247
	16 mA	136	197	197	-	-	-	166	197	197
	20 mA	138	187	187	-	-	-	154	187	187
	24 mA	134	177	177	-	-	-	143	177	177
3.3-V LVCMOS	4 mA	377	391	391	377	391	391	377	391	391
	8 mA	206	212	212	206	212	212	178	212	212
	12 mA	141	145	145	-	-	-	115	145	145
	16 mA	108	111	111	-	-	-	86	111	111
	20 mA	83	88	88	-	-	-	79	88	88
	24 mA	65	72	72	-	-	-	74	72	72
2.5-V LVTTTL/LVCMOS	4 mA	387	427	427	387	427	427	391	427	427
	8 mA	163	224	224	163	224	224	170	224	224
	12 mA	142	203	203	142	203	203	152	203	203
	16 mA	120	182	182	-	-	-	134	182	182

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 2 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
1.8-V LVTTTL/LVCMOS	2 mA	951	1421	1421	951	1421	1421	904	1421	1421
	4 mA	405	516	516	405	516	516	393	516	516
	6 mA	261	325	325	261	325	325	253	325	325
	8 mA	223	274	274	223	274	274	224	274	274
	10 mA	194	236	236	-	-	-	199	236	236
	12 mA	174	209	209	-	-	-	180	209	209
1.5-V LVTTTL/LVCMOS	2 mA	652	963	963	652	963	963	618	963	963
	4 mA	333	347	347	333	347	347	270	347	347
	6 mA	182	247	247	-	-	-	198	247	247
	8 mA	135	194	194	-	-	-	155	194	194
SSTL-2 Class I	8 mA	364	680	680	364	680	680	350	680	680
	12 mA	163	207	207	163	207	207	188	207	207
SSTL-2 Class II	16 mA	118	147	147	118	147	147	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116
SSTL-18 Class I	4 mA	458	570	570	458	570	570	505	570	570
	6 mA	305	380	380	305	380	380	336	380	380
	8 mA	225	282	282	225	282	282	248	282	282
	10 mA	167	220	220	167	220	220	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
SSTL-18 Class II	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
SSTL-2 Class I	8 mA	364	680	680	364	680	680	350	680	680
	12 mA	163	207	207	163	207	207	188	207	207
SSTL-2 Class II	16 mA	118	147	147	118	147	147	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 3 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
SSTL-18 Class I	4 mA	458	570	570	458	570	570	505	570	570
	6 mA	305	380	380	305	380	380	336	380	380
	8 mA	225	282	282	225	282	282	248	282	282
	10 mA	167	220	220	167	220	220	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
SSTL-18 Class II	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
1.8-V HSTL Class I	4 mA	245	282	282	245	282	282	229	282	282
	6 mA	164	188	188	164	188	188	153	188	188
	8 mA	123	140	140	123	140	140	114	140	140
	10 mA	110	124	124	110	124	124	108	124	124
	12 mA	97	110	110	97	110	110	104	110	110
1.8-V HSTL Class II	16 mA	101	104	104	-	-	-	99	104	104
	18 mA	98	102	102	-	-	-	93	102	102
	20 mA	93	99	99	-	-	-	88	99	99
1.5-V HSTL Class I	4 mA	168	196	196	168	196	196	188	196	196
	6 mA	112	131	131	112	131	131	125	131	131
	8 mA	84	99	99	84	99	99	95	99	99
	10 mA	87	98	98	-	-	-	90	98	98
	12 mA	86	98	98	-	-	-	87	98	98
1.5-V HSTL Class II	16 mA	95	101	101	-	-	-	96	101	101
	18 mA	95	100	100	-	-	-	101	100	100
	20 mA	94	101	101	-	-	-	104	101	101
Differential SSTL-2 Class II (3)	8 mA	364	680	680	-	-	-	350	680	680
	12 mA	163	207	207	-	-	-	188	207	207
	16 mA	118	147	147	-	-	-	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
Differential SSTL-18 Class I (3)	4 mA	458	570	570	-	-	-	505	570	570
	6 mA	305	380	380	-	-	-	336	380	380
	8 mA	225	282	282	-	-	-	248	282	282
	10 mA	167	220	220	-	-	-	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
Differential SSTL-18 Class II (3)	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
1.8-V Differential HSTL Class I (3)	4 mA	245	282	282	-	-	-	229	282	282
	6 mA	164	188	188	-	-	-	153	188	188
	8 mA	123	140	140	-	-	-	114	140	140
	10 mA	110	124	124	-	-	-	108	124	124
	12 mA	97	110	110	-	-	-	104	110	110
1.8-V Differential HSTL Class II (3)	16 mA	101	104	104	-	-	-	99	104	104
	18 mA	98	102	102	-	-	-	93	102	102
	20 mA	93	99	99	-	-	-	88	99	99
1.5-V Differential HSTL Class I (3)	4 mA	168	196	196	-	-	-	188	196	196
	6 mA	112	131	131	-	-	-	125	131	131
	8 mA	84	99	99	-	-	-	95	99	99
	10 mA	87	98	98	-	-	-	90	98	98
	12 mA	86	98	98	-	-	-	87	98	98
1.5-V Differential HSTL Class II (3)	16 mA	95	101	101	-	-	-	96	101	101
	18 mA	95	100	100	-	-	-	101	100	100
	20 mA	94	101	101	-	-	-	104	101	101
3.3-V PCI		134	177	177	-	-	-	143	177	177
3.3-V PCI-X		134	177	177	-	-	-	143	177	177
LVDS		-	-	-	155 (1)	155 (1)	155 (1)	134	134	134
HyperTransport technology		-	-	-	155 (1)	155 (1)	155 (1)	-	-	-
LVPECL (4)		-	-	-	-	-	-	134	134	134

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 5 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
3.3-V LVTTTL	OCT 50 Ω	133	152	152	133	152	152	147	152	152
2.5-V LVTTTL	OCT 50 Ω	207	274	274	207	274	274	235	274	274
1.8-V LVTTTL	OCT 50 Ω	151	165	165	151	165	165	153	165	165
3.3-V LVCMOS	OCT 50 Ω	300	316	316	300	316	316	263	316	316
1.5-V LVCMOS	OCT 50 Ω	157	171	171	157	171	171	174	171	171
SSTL-2 Class I	OCT 50 Ω	121	134	134	121	134	134	77	134	134
SSTL-2 Class II	OCT 25 Ω	56	101	101	56	101	101	58	101	101
SSTL-18 Class I	OCT 50 Ω	100	123	123	100	123	123	106	123	123
SSTL-18 Class II	OCT 25 Ω	61	110	110	-	-	-	59	110	110
1.2-V HSTL (2)	OCT 50 Ω	95	-	-	-	-	-	-	-	95

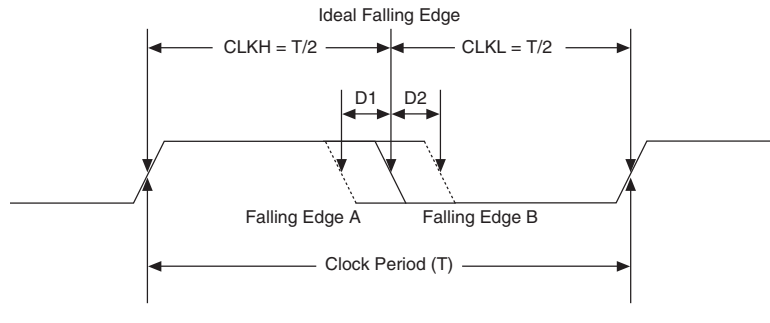
Notes to Table 5–79:

- (1) For LVDS and HyperTransport technology output on row I/O pins, the toggle rate derating factors apply to loads larger than 5 pF. In the derating calculation, subtract 5 pF from the intended load value in pF for the correct result. For a load less than or equal to 5 pF, refer to Table 5–78 for output toggle rates.
- (2) 1.2-V HSTL is only supported on column I/O pins in I/O banks 4,7, and 8.
- (3) Differential HSTL and SSTL is only supported on column clock and DQS outputs.
- (4) LVPECL is only supported on column clock outputs.

Duty Cycle Distortion

Duty cycle distortion (DCD) describes how much the falling edge of a clock is off from its ideal position. The ideal position is when both the clock high time (CLKH) and the clock low time (CLKL) equal half of the clock period (T), as shown in Figure 5–7. DCD is the deviation of the non-ideal falling edge from the ideal falling edge, such as D1 for the falling edge A and D2 for the falling edge B (Figure 5–7). The maximum DCD for a clock is the larger value of D1 and D2.

Figure 5-7. Duty Cycle Distortion



DCD expressed in absolute derivation, for example, D1 or D2 in [Figure 5-7](#), is clock-period independent. DCD can also be expressed as a percentage, and the percentage number is clock-period dependent. DCD as a percentage is defined as

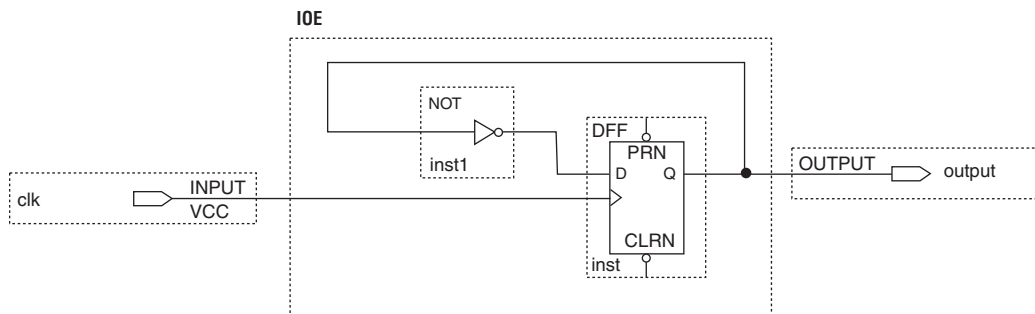
$$(T/2 - D1) / T \text{ (the low percentage boundary)}$$

$$(T/2 + D2) / T \text{ (the high percentage boundary)}$$

DCD Measurement Techniques

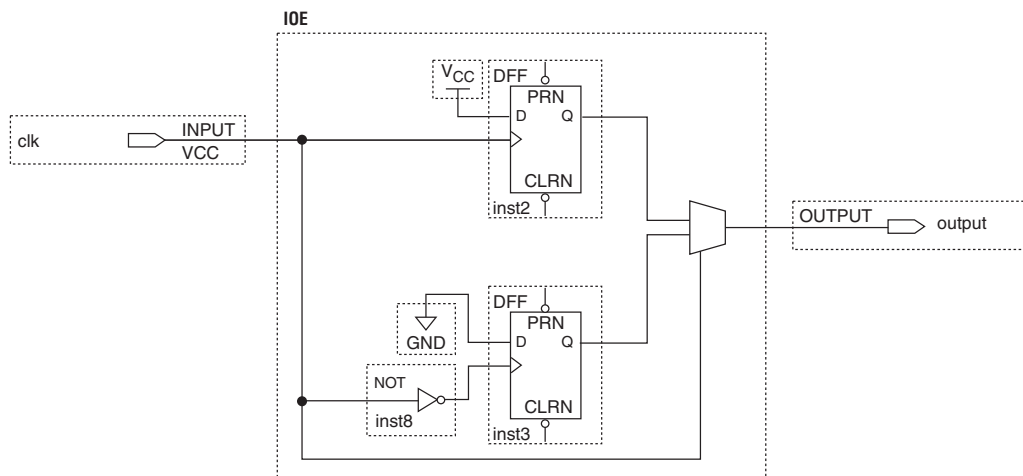
DCD is measured at an FPGA output pin driven by registers inside the corresponding I/O element (IOE) block. When the output is a single data rate signal (non-DDIO), only one edge of the register input clock (positive or negative) triggers output transitions ([Figure 5-8](#)). Therefore, any DCD present on the input clock signal or caused by the clock input buffer or different input I/O standard does not transfer to the output signal.

Figure 5-8. DCD Measurement Technique for Non-DDIO (Single-Data Rate) Outputs



However, when the output is a double data rate input/output (DDIO) signal, both edges of the input clock signal (positive and negative) trigger output transitions (Figure 5–9). Therefore, any distortion on the input clock and the input clock buffer affect the output DCD.

Figure 5–9. DCD Measurement Technique for DDIO (Double-Data Rate) Outputs



When an FPGA PLL generates the internal clock, the PLL output clocks the IOE block. As the PLL only monitors the positive edge of the reference clock input and internally re-creates the output clock signal, any DCD present on the reference clock is filtered out. Therefore, the DCD for a DDIO output with PLL in the clock path is better than the DCD for a DDIO output without PLL in the clock path.

Tables 5–80 through 5–87 give the maximum DCD in absolute derivation for different I/O standards on Stratix II devices. Examples are also provided that show how to calculate DCD as a percentage.

Table 5–80. Maximum DCD for Non-DDIO Output on Row I/O Pins (Part 1 of 2) Note (1)

Row I/O Output Standard	Maximum DCD for Non-DDIO Output		
	-3 Devices	-4 & -5 Devices	Unit
3.3-V LVTTTL	245	275	ps
3.3-V LVCMOS	125	155	ps
2.5 V	105	135	ps

Table 5–80. Maximum DCD for Non-DDIO Output on Row I/O Pins (Part 2 of 2) <i>Note (1)</i>			
Row I/O Output Standard	Maximum DCD for Non-DDIO Output		
	-3 Devices	-4 & -5 Devices	Unit
1.8 V	180	180	ps
1.5-V LVCMOS	165	195	ps
SSTL-2 Class I	115	145	ps
SSTL-2 Class II	95	125	ps
SSTL-18 Class I	55	85	ps
1.8-V HSTL Class I	80	100	ps
1.5-V HSTL Class I	85	115	ps
LVDS/ HyperTransport technology	55	80	ps

Note to Table 5–80:

- (1) The DCD specification is based on a no logic array noise condition.

Here is an example for calculating the DCD as a percentage for a non-DDIO output on a row I/O on a -3 device:

If the non-DDIO output I/O standard is SSTL-2 Class II, the maximum DCD is 95 ps (see Table 5–80). If the clock frequency is 267 MHz, the clock period T is:

$$T = 1 / f = 1 / 267 \text{ MHz} = 3.745 \text{ ns} = 3745 \text{ ps}$$

To calculate the DCD as a percentage:

$$(T/2 - \text{DCD}) / T = (3745\text{ps}/2 - 95\text{ps}) / 3745\text{ps} = 47.5\% \text{ (for low boundary)}$$

$$(T/2 + \text{DCD}) / T = (3745\text{ps}/2 + 95\text{ps}) / 3745\text{ps} = 52.5\% \text{ (for high boundary)}$$

Therefore, the DCD percentage for the 267 MHz SSTL-2 Class II non-DDIO row output clock on a -3 device ranges from 47.5% to 52.5%.

Column I/O Output Standard I/O Standard	Maximum DCD for Non-DDIO Output		Unit
	-3 Devices	-4 & -5 Devices	
3.3-V LVTTTL	190	220	ps
3.3-V LVCMOS	140	175	ps
2.5 V	125	155	ps
1.8 V	80	110	ps
1.5-V LVCMOS	185	215	ps
SSTL-2 Class I	105	135	ps
SSTL-2 Class II	100	130	ps
SSTL-18 Class I	90	115	ps
SSTL-18 Class II	70	100	ps
1.8-V HSTL Class I	80	110	ps
1.8-V HSTL Class II	80	110	ps
1.5-V HSTL Class I	85	115	ps
1.5-V HSTL Class II	50	80	ps
1.2-V HSTL (2)	170	-	ps
LVPECL	55	80	ps

Notes to Table 5–81:

- (1) The DCD specification is based on a no logic array noise condition.
- (2) 1.2-V HSTL is only supported in -3 devices.

Table 5–82. Maximum DCD for DDIO Output on Row I/O Pins Without PLL in the Clock Path for -3 Devices *Notes (1), (2)*

Row DDIO Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	LVDS/ HyperTransport Technology	
	3.3 & 2.5 V	1.8 & 1.5 V	2.5 V	1.8 & 1.5 V	3.3 V	
3.3-V LVTTTL	260	380	145	145	110	ps
3.3-V LVCMOS	210	330	100	100	65	ps
2.5 V	195	315	85	85	75	ps
1.8 V	150	265	85	85	120	ps
1.5-V LVCMOS	255	370	140	140	105	ps
SSTL-2 Class I	175	295	65	65	70	ps
SSTL-2 Class II	170	290	60	60	75	ps
SSTL-18 Class I	155	275	55	50	90	ps
1.8-V HSTL Class I	150	270	60	60	95	ps
1.5-V HSTL Class I	150	270	55	55	90	ps
LVDS/ HyperTransport technology	180	180	180	180	180	ps

Notes to Table 5–82:

- (1) The information in Table 5–82 assumes the input clock has zero DCD.
- (2) The DCD specification is based on a no logic array noise condition.

Here is an example for calculating the DCD in percentage for a DDIO output on a row I/O on a -3 device:

If the input I/O standard is SSTL-2 and the DDIO output I/O standard is SSTL-2 Class II, the maximum DCD is 60 ps (see Table 5–82). If the clock frequency is 267 MHz, the clock period T is:

$$T = 1 / f = 1 / 267 \text{ MHz} = 3.745 \text{ ns} = 3745 \text{ ps}$$

Calculate the DCD as a percentage:

$$(T/2 - \text{DCD}) / T = (3745\text{ps}/2 - 60\text{ps}) / 3745\text{ps} = 48.4\% \text{ (for low boundary)}$$

$$(T/2 + \text{DCD}) / T = (3745 \text{ ps}/2 + 60 \text{ ps}) / 3745\text{ps} = 51.6\% \text{ (for high boundary)}$$

Therefore, the DCD percentage for the 267 MHz SSTL-2 Class II DDIO row output clock on a -3 device ranges from 48.4% to 51.6%.

Table 5–83. Maximum DCD for DDIO Output on Row I/O Pins Without PLL in the Clock Path for -4 & -5 Devices Notes (1), (2)

Row DDIO Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	LVDS/ HyperTransport Technology	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	3.3 V	
3.3-V LVTTTL	440	495	170	160	105	ps
3.3-V LVCMOS	390	450	120	110	75	ps
2.5 V	375	430	105	95	90	ps
1.8 V	325	385	90	100	135	ps
1.5-V LVCMOS	430	490	160	155	100	ps
SSTL-2 Class I	355	410	85	75	85	ps
SSTL-2 Class II	350	405	80	70	90	ps
SSTL-18 Class I	335	390	65	65	105	ps
1.8-V HSTL Class I	330	385	60	70	110	ps
1.5-V HSTL Class I	330	390	60	70	105	ps
LVDS/ HyperTransport technology	180	180	180	180	180	ps

Notes to Table 5–83:

- (1) Table 5–83 assumes the input clock has zero DCD.
- (2) The DCD specification is based on a no logic array noise condition.

Table 5–84. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -3 Devices (Part 1 of 2) Notes (1), (2)

DDIO Column Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	1.2-V HSTL	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	1.2 V	
3.3-V LVTTTL	260	380	145	145	145	ps
3.3-V LVCMOS	210	330	100	100	100	ps
2.5 V	195	315	85	85	85	ps

Table 5–84. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -3 Devices (Part 2 of 2) Notes (1), (2)

DDIO Column Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	1.2-V HSTL	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	1.2 V	
1.8 V	150	265	85	85	85	ps
1.5-V LVCMOS	255	370	140	140	140	ps
SSTL-2 Class I	175	295	65	65	65	ps
SSTL-2 Class II	170	290	60	60	60	ps
SSTL-18 Class I	155	275	55	50	50	ps
SSTL-18 Class II	140	260	70	70	70	ps
1.8-V HSTL Class I	150	270	60	60	60	ps
1.8-V HSTL Class II	150	270	60	60	60	ps
1.5-V HSTL Class I	150	270	55	55	55	ps
1.5-V HSTL Class II	125	240	85	85	85	ps
1.2-V HSTL	240	360	155	155	155	ps
LVPECL	180	180	180	180	180	ps

Notes to Table 5–84:

- (1) Table 5–84 assumes the input clock has zero DCD.
- (2) The DCD specification is based on a no logic array noise condition.

Table 5–85. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -4 & -5 Devices (Part 1 of 2) Notes (1), (2)

DDIO Column Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)				Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	
3.3-V LVTTTL	440	495	170	160	ps
3.3-V LVCMOS	390	450	120	110	ps
2.5 V	375	430	105	95	ps
1.8 V	325	385	90	100	ps
1.5-V LVCMOS	430	490	160	155	ps
SSTL-2 Class I	355	410	85	75	ps
SSTL-2 Class II	350	405	80	70	ps

Table 5–85. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -4 & -5 Devices (Part 2 of 2) *Notes (1), (2)*

DDIO Column Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)				Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	
SSTL-18 Class I	335	390	65	65	ps
SSTL-18 Class II	320	375	70	80	ps
1.8-V HSTL Class I	330	385	60	70	ps
1.8-V HSTL Class II	330	385	60	70	ps
1.5-V HSTL Class I	330	390	60	70	ps
1.5-V HSTL Class II	330	360	90	100	ps
1.2-V HSTL	420	470	155	165	ps
LVPECL	180	180	180	180	ps

Notes to Table 5–85:

- (1) Table 5–85 assumes the input clock has zero DCD.
- (2) The DCD specification is based on a no logic array noise condition.

Table 5–86. Maximum DCD for DDIO Output on Row I/O Pins with PLL in the Clock Path (Part 1 of 2) *Note (1)*

Row DDIO Output I/O Standard	Maximum DCD (PLL Output Clock Feeding DDIO Clock Port)		Unit
	-3 Device	-4 & -5 Device	
3.3-V LVTTTL	110	105	ps
3.3-V LVCMOS	65	75	ps
2.5V	75	90	ps
1.8V	85	100	ps
1.5-V LVCMOS	105	100	ps
SSTL-2 Class I	65	75	ps
SSTL-2 Class II	60	70	ps
SSTL-18 Class I	50	65	ps
1.8-V HSTL Class I	50	70	ps
1.5-V HSTL Class I	55	70	ps

Table 5–86. Maximum DCD for DDIO Output on Row I/O Pins with PLL in the Clock Path (Part 2 of 2) *Note (1)*

Row DDIO Output I/O Standard	Maximum DCD (PLL Output Clock Feeding DDIO Clock Port)		Unit
	-3 Device	-4 & -5 Device	
LVDS/ HyperTransport technology	180	180	ps

Note to Table 5–86:

- (1) The DCD specification is based on a no logic array noise condition.

Table 5–87. Maximum DCD for DDIO Output on Column I/O with PLL in the Clock Path *Note (1)*

Column DDIO Output I/O Standard	Maximum DCD (PLL Output Clock Feeding DDIO Clock Port)		Unit
	-3 Device	-4 & -5 Device	
3.3-V LVTTTL	145	160	ps
3.3-V LVCMOS	100	110	ps
2.5V	85	95	ps
1.8V	85	100	ps
1.5-V LVCMOS	140	155	ps
SSTL-2 Class I	65	75	ps
SSTL-2 Class II	60	70	ps
SSTL-18 Class I	50	65	ps
SSTL-18 Class II	70	80	ps
1.8-V HSTL Class I	60	70	ps
1.8-V HSTL Class II	60	70	ps
1.5-V HSTL Class I	55	70	ps
1.5-V HSTL Class II	85	100	ps
1.2-V HSTL	155	-	ps
LVPECL	180	180	ps

Notes to Table 5–87:

- (1) The DCD specification is based on a no logic array noise condition.
 (2) 1.2-V HSTL is only supported in -3 devices.

High-Speed I/O Specifications

Table 5–88 provides high-speed timing specifications definitions.

High-Speed Timing Specifications	Definitions
t_C	High-speed receiver/transmitter input and output clock period.
f_{HSCLK}	High-speed receiver/transmitter input and output clock frequency.
J	Deserialization factor (width of parallel data bus).
W	PLL multiplication factor.
t_{RISE}	Low-to-high transmission time.
t_{FALL}	High-to-low transmission time.
Timing unit interval (TUI)	The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency × Multiplication Factor) = t_C/w).
f_{HSDR}	Maximum/minimum LVDS data transfer rate ($f_{HSDR} = 1/TUI$), non-DPA.
$f_{HSDRDPA}$	Maximum/minimum LVDS data transfer rate ($f_{HSDRDPA} = 1/TUI$), DPA.
Channel-to-channel skew (TCCS)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
Sampling window (SW)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window.
Input jitter	Peak-to-peak input jitter on high-speed PLLs.
Output jitter	Peak-to-peak output jitter on high-speed PLLs.
t_{DUTY}	Duty cycle on high-speed transmitter output clock.
t_{LOCK}	Lock time for high-speed transmitter and receiver PLLs.

Table 5–89 shows the high-speed I/O timing specifications for -3 speed grade Stratix II devices.

Symbol	Conditions	-3 Speed Grade			Unit
		Min	Typ	Max	
f_{HSCLK} (clock frequency) $f_{HSCLK} = f_{HSDR} / W$	W = 2 to 32 (LVDS, HyperTransport technology) (3)	16		520	MHz
	W = 1 (SERDES bypass, LVDS only)	16		500	MHz
	W = 1 (SERDES used, LVDS only)	150		717	MHz

Symbol	Conditions			-3 Speed Grade			Unit
				Min	Typ	Max	
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
	J = 2 (LVDS, HyperTransport technology)			(4)		760	Mbps
	J = 1 (LVDS only)			(4)		500	Mbps
f_{HSDRDPA} (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
TCCS	All differential standards			-		200	ps
SW	All differential standards			330		-	ps
Output jitter						190	ps
Output t_{RISE}	All differential I/O standards					160	ps
Output t_{FALL}	All differential I/O standards					180	ps
t_{DUTY}				45	50	55	%
DPA run length						6,400	UI
DPA jitter tolerance	Data channel peak-to-peak jitter			0.44			UI
DPA lock time	Standard	Training Pattern	Transition Density				Number of repetitions
	SPI-4	0000000000 1111111111	10%	256			
	Parallel Rapid I/O	00001111	25%	256			
		10010000	50%	256			
	Miscellaneous	10101010	100%	256			
01010101			256				

Notes to Table 5–89:

- (1) When J = 4 to 10, the SERDES block is used.
- (2) When J = 1 or 2, the SERDES block is bypassed.
- (3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: $150 \leq \text{input clock frequency} \times W \leq 1,040$.
- (4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.

Table 5–90 shows the high-speed I/O timing specifications for -4 speed grade Stratix II devices.

Symbol	Conditions	-4 Speed Grade			Unit	
		Min	Typ	Max		
f_{HSCLK} (clock frequency) $f_{\text{HSCLK}} = f_{\text{HSDR}} / W$	W = 2 to 32 (LVDS, HyperTransport technology) (3)	16		520	MHz	
	W = 1 (SERDES bypass, LVDS only)	16		500	MHz	
	W = 1 (SERDES used, LVDS only)	150		717	MHz	
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)	150		1,040	Mbps	
	J = 2 (LVDS, HyperTransport technology)	(4)		760	Mbps	
	J = 1 (LVDS only)	(4)		500	Mbps	
f_{HSDRDPA} (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)	150		1,040	Mbps	
TCCS	All differential standards	-		200	ps	
SW	All differential standards	330		-	ps	
Output jitter				190	ps	
Output t_{RISE}	All differential I/O standards			160	ps	
Output t_{FALL}	All differential I/O standards			180	ps	
t_{DUTY}		45	50	55	%	
DPA run length				6,400	UI	
DPA jitter tolerance	Data channel peak-to-peak jitter	0.44			UI	
DPA lock time	Standard	Training Pattern	Transition Density			Number of repetitions
	SPI-4	0000000000 1111111111	10%	256		
	Parallel Rapid I/O	00001111	25%	256		
		10010000	50%	256		
	Miscellaneous	10101010	100%	256		
01010101			256			

Notes to Table 5–90:

- (1) When J = 4 to 10, the SERDES block is used.
- (2) When J = 1 or 2, the SERDES block is bypassed.
- (3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: $150 \leq \text{input clock frequency} \times W \leq 1,040$.
- (4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.

Table 5–91 shows the high-speed I/O timing specifications for -5 speed grade Stratix II devices.

Symbol	Conditions	-5 Speed Grade			Unit	
		Min	Typ	Max		
f_{HSCLK} (clock frequency) $f_{\text{HSCLK}} = f_{\text{HSDR}} / W$	W = 2 to 32 (LVDS, HyperTransport technology) (3)	16		420	MHz	
	W = 1 (SERDES bypass, LVDS only)	16		500	MHz	
	W = 1 (SERDES used, LVDS only)	150		640	MHz	
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)	150		840	Mbps	
	J = 2 (LVDS, HyperTransport technology)	(4)		700	Mbps	
	J = 1 (LVDS only)	(4)		500	Mbps	
f_{HSDRDPA} (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)	150		840	Mbps	
TCCS	All differential I/O standards	-		200	ps	
SW	All differential I/O standards	440		-	ps	
Output jitter				190	ps	
Output t_{RISE}	All differential I/O standards			290	ps	
Output t_{FALL}	All differential I/O standards			290	ps	
t_{DUTY}		45	50	55	%	
DPA run length				6,400	UI	
DPA jitter tolerance	Data channel peak-to-peak jitter	0.44			UI	
DPA lock time	Standard	Training Pattern	Transition Density			Number of repetitions
	SPI-4	0000000000 1111111111	10%	256		
	Parallel Rapid I/O	00001111	25%	256		
		10010000	50%	256		
	Miscellaneous	10101010	100%	256		
01010101			256			

Notes to Table 5–91:

- (1) When J = 4 to 10, the SERDES block is used.
- (2) When J = 1 or 2, the SERDES block is bypassed.
- (3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: $150 \leq \text{input clock frequency} \times W \leq 1,040$.
- (4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.

PLL Timing Specifications

Tables 5–92 and 5–93 describe the Stratix II PLL specifications when operating in both the commercial junction temperature range (0 to 85 °C) and the industrial junction temperature range (–40 to 100 °C).

Table 5–92. Enhanced PLL Specifications (Part 1 of 2)

Name	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	2		500	MHz
f_{INPFD}	Input frequency to the PFD	2		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
$f_{EINDUTY}$	External feedback input clock duty cycle	40		60	%
$t_{INJITTER}$	Input or external feedback clock input jitter tolerance in terms of period jitter. Bandwidth \leq 0.85 MHz		0.5		ns (p-p)
	Input or external feedback clock input jitter tolerance in terms of period jitter. Bandwidth $>$ 0.85 MHz		1.0		ns (p-p)
$t_{OUTJITTER}$	Dedicated clock output period jitter			250 ps for \geq 100 MHz out_{clk} 25 mUI for $<$ 100 MHz out_{clk}	ps or mUI (p-p)
t_{FCOMP}	External feedback compensation time			10	ns
f_{OUT}	Output frequency for internal global or regional clock	1.5 (2)		550.0	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%).	45	50	55	%
$f_{SCANCLK}$	Scanclk frequency			100	MHz
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for enhanced PLLs		$174/f_{SCANCLK}$		ns
f_{OUT_EXT}	PLL external clock output frequency	1.5 (2)		550.0 (1)	MHz

Table 5–92. Enhanced PLL Specifications (Part 2 of 2)

Name	Description	Min	Typ	Max	Unit
t_{LOCK}	Time required for the PLL to lock from the time it is enabled or the end of device configuration		0.03	1	ms
t_{DLOCK}	Time required for the PLL to lock dynamically after automatic clock switchover between two identical clock frequencies			1	ms
$f_{SWITCHOVER}$	Frequency range where the clock switchover performs properly	4		500	MHz
f_{CLBW}	PLL closed-loop bandwidth	0.13	1.20	16.90	MHz
f_{VCO}	PLL VCO operating range for –3 and –4 speed grade devices	300		1,040	MHz
	PLL VCO operating range for –5 speed grade devices	300		840	MHz
f_{SS}	Spread-spectrum modulation frequency	30		150	kHz
% spread	Percent down spread for a given clock frequency	0.4	0.5	0.6	%
t_{PLL_PSERR}	Accuracy of PLL phase shift			±15	ps
t_{ARESET}	Minimum pulse width on <code>areset</code> signal.	10			ns
$t_{ARESET_RECONFIG}$	Minimum pulse width on the <code>areset</code> signal when using PLL reconfiguration. Reset the PLL after <code>scandone</code> goes high.	500			ns

Notes to Table 5–92:

- (1) Limited by I/O f_{MAX} . See Table 5–78 on page 5–69 for the maximum. Cannot exceed f_{OUT} specification.
- (2) If the counter cascading feature of the PLL is utilized, there is no minimum output clock frequency.

Table 5–93. Fast PLL Specifications

Name	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (for -3 and -4 speed grade devices)	16.08		717	MHz
	Input clock frequency (for -5 speed grade devices)	16.08		640	MHz
f_{INPFD}	Input frequency to the PFD	16.08		500	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
$t_{INJITTER}$	Input clock jitter tolerance in terms of period jitter. Bandwidth ≤ 2 MHz		0.5		ns (p-p)
	Input clock jitter tolerance in terms of period jitter. Bandwidth > 2 MHz		1.0		ns (p-p)
f_{VCO}	Upper VCO frequency range for -3 and -4 speed grades	300		1,040	MHz
	Upper VCO frequency range for -5 speed grades	300		840	MHz
	Lower VCO frequency range for -3 and -4 speed grades	150		520	MHz
	Lower VCO frequency range for -5 speed grades	150		420	MHz
f_{OUT}	PLL output frequency to <i>GCLK</i> or <i>RCLK</i>	4.6875		550	MHz
	PLL output frequency to LVDS or DPA clock	150		1,040	MHz
f_{OUT_IO}	PLL clock output frequency to regular I/O pin	4.6875		(1)	MHz
$f_{SCANCLK}$	Scanclk frequency			100	MHz
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for fast PLLs		$75/f_{SCANCLK}$		ns
f_{CLBW}	PLL closed-loop bandwidth	1.16	5.00	28.00	MHz
t_{LOCK}	Time required for the PLL to lock from the time it is enabled or the end of the device configuration		0.03	1.00	ms
t_{PLL_PSERR}	Accuracy of PLL phase shift			± 15	ps
t_{ARESET}	Minimum pulse width on <i>areset</i> signal.	10			ns
$t_{ARESET_RECONFIG}$	Minimum pulse width on the <i>areset</i> signal when using PLL reconfiguration. Reset the PLL after <i>scandone</i> goes high.	500			ns

Note to Table 5–93:

(1) Limited by I/O f_{MAX} . See Table 5–77 on page 5–67 for the maximum.

External Memory Interface Specifications

Tables 5–94 through 5–101 contain Stratix II device specifications for the dedicated circuitry used for interfacing with external memory devices.

Table 5–94. DLL Frequency Range Specifications

Frequency Mode	Frequency Range	Resolution (Degrees)
0	100 to 175	30
1	150 to 230	22.5
2	200 to 310	30
3	240 to 400 (–3 speed grade)	36
	240 to 350 (–4 and –5 speed grades)	36

Table 5–95 lists the maximum delay in the fast timing model for the Stratix II DQS delay buffer. Multiply the number of delay buffers that you are using in the DQS logic block to get the maximum delay achievable in your system. For example, if you implement a 90° phase shift at 200 MHz, you use three delay buffers in mode 2. The maximum achievable delay from the DQS block is then $3 \times .416 \text{ ps} = 1.248 \text{ ns}$.

Table 5–95. DQS Delay Buffer Maximum Delay in Fast Timing Model

Frequency Mode	Maximum Delay Per Delay Buffer (Fast Timing Model)	Unit
0	0.833	ns
1, 2, 3	0.416	ns

Table 5–96. DQS Period Jitter Specifications for DLL-Delayed Clock (iDQS_JITTER) Note (1)

Number of DQS Delay Buffer Stages (2)	Commercial	Industrial	Unit
1	80	110	ps
2	110	130	ps
3	130	180	ps
4	160	210	ps

Notes to Table 5–96:

- (1) Peak-to-peak period jitter on the phase shifted DQS clock.
- (2) Delay stages used for requested DQS phase shift are reported in your project's Compilation Report in the Quartus II software.

Table 5–97. DQS Phase Jitter Specifications for DLL-Delayed Clock (tDQS_PHASE_JITTER) Note (1)

Number of DQS Delay Buffer Stages (2)	DQS Phase Jitter	Unit
1	30	ps
2	60	ps
3	90	ps
4	120	ps

Notes to Table 5–97:

- (1) Peak-to-peak phase jitter on the phase shifted DDS clock (digital jitter is caused by DLL tracking).
- (2) Delay stages used for requested DQS phase shift are reported in your project's Compilation Report in the Quartus II software.

Table 5–98. DQS Phase-Shift Error Specifications for DLL-Delayed Clock (tDQS_PSERR) (1)

Number of DQS Delay Buffer Stages (2)	–3 Speed Grade	–4 Speed Grade	–5 Speed Grade	Unit
1	25	30	35	ps
2	50	60	70	ps
3	75	90	105	ps
4	100	120	140	ps

Notes to Table 5–98:

- (1) This error specification is the absolute maximum and minimum error. For example, skew on three delay buffer stages in a C3 speed grade is 75 ps or ± 37.5 ps.
- (2) Delay stages used for requested DQS phase shift are reported in your project's Compilation Report in the Quartus II software.

Table 5–99. DQS Bus Clock Skew Adder Specifications (tDQS_CLOCK_SKEW_ADDER)

Mode	DQS Clock Skew Adder	Unit
×4 DQ per DQS	40	ps
×9 DQ per DQS	70	ps
×18 DQ per DQS	75	ps
×36 DQ per DQS	95	ps

Note to Table 5–99:

- (1) This skew specification is the absolute maximum and minimum skew. For example, skew on a ×4 DQ group is 40 ps or ± 20 ps.

Table 5–100. DQS Phase Offset Delay Per Stage *Notes (1), (2), (3)*

Speed Grade	Min	Max	Unit
-3	9	14	ps
-4	9	14	ps
-5	9	15	ps

Notes to Table 5–100:

- (1) The delay settings are linear.
- (2) The valid settings for phase offset are -64 to +63 for frequency mode 0 and -32 to +31 for frequency modes 1, 2, and 3.
- (3) The typical value equals the average of the minimum and maximum values.

Table 5–101. DDIO Outputs Half-Period Jitter *Notes (1), (2)*

Name	Description	Max	Unit
$t_{OUTHALFJITTER}$	Half-period jitter (PLL driving DDIO outputs)	200	ps

Notes to Table 5–101:

- (1) The worst-case half period is equal to the ideal half period subtracted by the DCD and half-period jitter values.
- (2) The half-period jitter was characterized using a PLL driving DDIO outputs.

JTAG Timing Specifications

Figure 5–10 shows the timing requirements for the JTAG signals.

Figure 5–10. Stratix II JTAG Waveforms

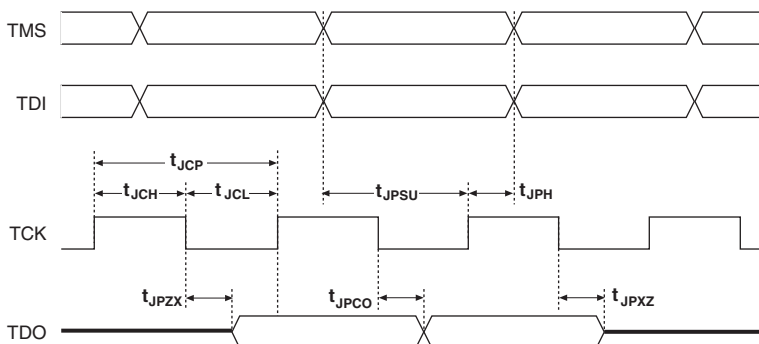


Table 5–102 shows the JTAG timing parameters and values for Stratix II devices.

Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	30		ns
t_{JCH}	TCK clock high time	13		ns
t_{JCL}	TCK clock low time	13		ns
t_{JPSU}	JTAG port setup time	3		ns
t_{JPH}	JTAG port hold time	5		ns
t_{JPCO}	JTAG port clock to output		11 (1)	ns
t_{JPZX}	JTAG port high impedance to valid output		14 (1)	ns
t_{JPXZ}	JTAG port valid output to high impedance		14 (1)	ns

Note to Table 5–102:

- (1) A 1 ns adder is required for each V_{CCIO} voltage step down from 3.3 V. For example, $t_{JPCO} = 12$ ns if V_{CCIO} of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.

Document Revision History

Table 5–103 shows the revision history for this chapter.

Date and Document Version	Changes Made	Summary of Changes
April 2011, v4.5	Updated Table 5–3.	Added operating junction temperature for military use.
July 2009, v4.4	Updated Table 5–92.	Updated the spread spectrum modulation frequency (f_{SS}) from (100 kHz–500 kHz) to (30 kHz–150 kHz).
May 2007, v4.3	<ul style="list-style-type: none"> • Updated R_{CONF} in Table 5–4. • Updated f_{IN} (min) in Table 5–92. • Updated f_{IN} and f_{INPFD} in Table 5–93. 	—
	Moved the Document Revision History section to the end of the chapter.	—

Table 5–103. Document Revision History (Part 2 of 3)		
Date and Document Version	Changes Made	Summary of Changes
August, 2006, v4.2	Updated Table 5–73, Table 5–75, Table 5–77, Table 5–78, Table 5–79, Table 5–81, Table 5–85, and Table 5–87.	—
April 2006, v4.1	<ul style="list-style-type: none"> ● Updated Table 5–3. ● Updated Table 5–11. ● Updated Figures 5–8 and 5–9. ● Added parallel on-chip termination information to “On-Chip Termination Specifications” section. ● Updated Tables 5–28, 5–30, 5–31, and 5–34. ● Updated Table 5–78, Tables 5–81 through 5–90, and Tables 5–92, 5–93, and 5–98. ● Updated “PLL Timing Specifications” section. ● Updated “External Memory Interface Specifications” section. ● Added Tables 5–95 and 5–101. ● Updated “JTAG Timing Specifications” section, including Figure 5–10 and Table 5–102. 	<ul style="list-style-type: none"> ● Changed 0.2 MHz to 2 MHz in Table 5–93. ● Added new spec for half period jitter (Table 5–101). ● Added support for PLL clock switchover for industrial temperature range. ● Changed f_{INPFD} (min) spec from 4 MHz to 2 MHz in Table 5–92. ● Fixed typo in $t_{OUTJITTER}$ specification in Table 5–92. ● Updated V_{DIF} AC & DC max specifications in Table 5–28. ● Updated minimum values for t_{JCH}, t_{JCL}, and t_{JPSU} in Table 5–102. ● Update maximum values for t_{JPCO}, t_{JPZX}, and t_{JPXZ} in Table 5–102.
December 2005, v4.0	<ul style="list-style-type: none"> ● Updated “External Memory Interface Specifications” section. ● Updated timing numbers throughout chapter. 	—
July 2005, v3.1	<ul style="list-style-type: none"> ● Updated HyperTransport technology information in Table 5–13. ● Updated “Timing Model” section. ● Updated “PLL Timing Specifications” section. ● Updated “External Memory Interface Specifications” section. 	—
May 2005, v3.0	<ul style="list-style-type: none"> ● Updated tables throughout chapter. ● Updated “Power Consumption” section. ● Added various tables. ● Replaced “Maximum Input & Output Clock Rate” section with “Maximum Input & Output Clock Toggle Rate” section. ● Added “Duty Cycle Distortion” section. ● Added “External Memory Interface Specifications” section. 	—
March 2005, v2.2	Updated tables in “Internal Timing Parameters” section.	—
January 2005, v2.1	Updated input rise and fall time.	—

Table 5–103. Document Revision History (Part 3 of 3)

Date and Document Version	Changes Made	Summary of Changes
January 2005, v2.0	<ul style="list-style-type: none"> ● Updated the “Power Consumption” section. ● Added the “High-Speed I/O Specifications” and “On-Chip Termination Specifications” sections. ● Removed the ESD Protection Specifications section. ● Updated Tables 5–3 through 5–13, 5–16 through 5–18, 5–21, 5–35, 5–39, and 5–40. ● Updated tables in “Timing Model” section. ● Added Tables 5–30 and 5–31. 	—
October 2004, v1.2	<ul style="list-style-type: none"> ● Updated Table 5–3. ● Updated introduction text in the “PLL Timing Specifications” section. 	—
July 2004, v1.1	<ul style="list-style-type: none"> ● Re-organized chapter. ● Added typical values and C_{OUTFB} to Table 5–32. ● Added undershoot specification to Note (4) for Tables 5–1 through 5–9. ● Added Note (1) to Tables 5–5 and 5–6. ● Added V_{ID} and V_{ICM} to Table 5–10. ● Added “I/O Timing Measurement Methodology” section. ● Added Table 5–72. ● Updated Tables 5–1 through 5–2 and Tables 5–24 through 5–29. 	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—

